



PowerPC 740™ and PowerPC 750™ Embedded Microprocessor Datasheet

IBM CMOS 0.20 μm Copper Technology EMPPC740L and EMPPC750L

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**PowerPC 740 and PowerPC 750 Embedded Microprocessor
IBM CMOS 0.20 um Copper Technology EMPPC740L and EMPPC750L**



Preface

The PowerPC 740 and PowerPC 750 embedded microprocessors are implementations of the PowerPC™ family of reduced instruction set computer (RISC) microprocessors. This document covers PowerPC 740 and PowerPC 750 microprocessors using the IBM CMOS 7S 0.20 um copper technology. In this document, “740” refers to the PowerPC 740 microprocessor, and “750” refers to the PowerPC 750 microprocessor, with the document’s primary focus on the features of the 750 microprocessor; however, unless otherwise noted, all features apply equally to the 740 microprocessor.

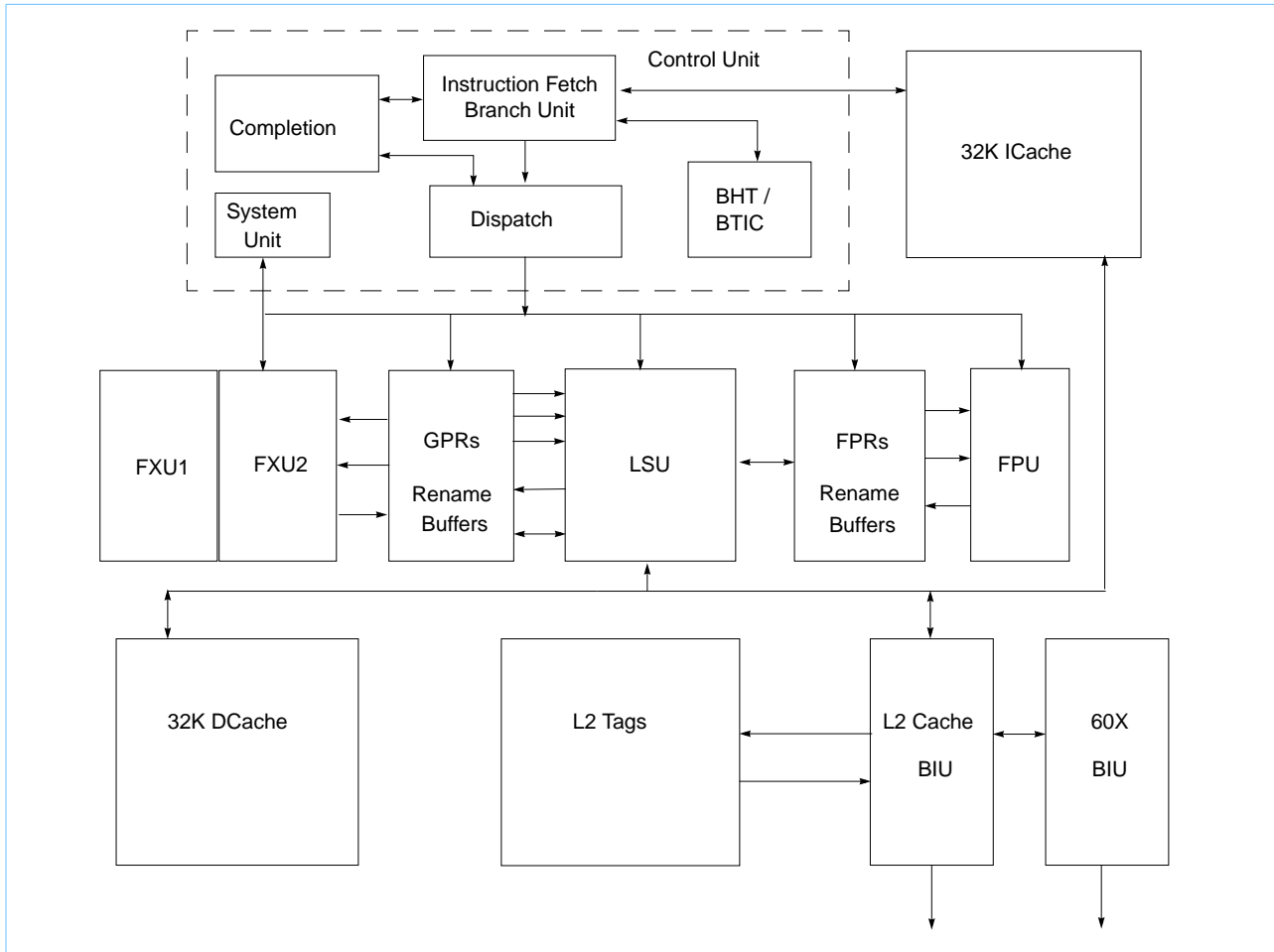
The 740 uses the same die as the 750, but the 740 does not pin out the L2 cache interface.

Overview

The 750 is targeted for high performance, low power systems and supports the following power management features: doze, nap, sleep, and dynamic power management. The 750 consists of a processor core and an internal L2 Tag combined with a dedicated L2 cache interface and a 60x bus. The L2 cache is not available with the 740.

Figure 1 shows a block diagram of the 750.

Figure 1. 750 Block Diagram



Features

This section summarizes features of the implementation of the PowerPC 750 architecture. Major features are as follows.

- Branch processing unit
 - Four instructions fetched per clock.
 - One branch processed per cycle (plus resolving 2 speculations).
 - Up to 1 speculative stream in execution, 1 additional speculative stream in fetch.
 - 512-entry branch history table (BHT) for dynamic prediction.
 - 64-entry, 4-way set associative branch target instruction cache (BTIC) for eliminating branch delay slots.
- Dispatch unit
 - Full hardware detection of dependencies (resolved in the execution units).
 - Dispatch two instructions to six independent units (system, branch, load/store, fixed-point unit 1, fixed-point unit 2, or floating-point).
 - Serialization control (predispatch, postdispatch, execution, serialization).
- Decode
 - Register file access.
 - Forwarding control.
 - Partial instruction decode.
- Load/store unit
 - One cycle load or store cache access (byte, half-word, word, double-word).
 - Effective address generation.
 - Hits under misses (one outstanding miss).
 - Single-cycle misaligned access within double word boundary.
 - Alignment, zero padding, sign extend for integer register file.
 - Floating-point internal format conversion (alignment, normalization).
 - Sequencing for load/store multiples and string operations.
 - Store gathering.
 - Cache and TLB instructions.
 - Big and little-endian byte addressing supported.
 - Misaligned little-endian support in hardware.
- Fixed-point units
 - Fixed-point unit 1 (FXU1); multiply, divide, shift, rotate, arithmetic, logical.
 - Fixed-point unit 2 (FXU2); shift, rotate, arithmetic, logical.
 - Single-cycle arithmetic, shift, rotate, logical.
 - Multiply and divide support (multi-cycle).
 - Early out multiply.

- Floating-point unit
 - Support for IEEE-754 standard single- and double-precision floating-point arithmetic.
 - 3 cycle latency, 1 cycle throughput, single-precision multiply-add.
 - 3 cycle latency, 1 cycle throughput, double-precision add.
 - 4 cycle latency, 2 cycle throughput, double-precision multiply-add.
 - Hardware support for divide.
 - Hardware support for denormalized numbers.
 - Time deterministic non-IEEE mode.
- System unit
 - Executes CR logical instructions and miscellaneous system instructions.
 - Special register transfer instructions.
- Cache structure
 - 32K, 32-byte line, 8-way set associative instruction cache.
 - 32K, 32-byte line, 8-way set associative data cache.
 - Single-cycle cache access.
 - Pseudo-LRU replacement.
 - Copy-back or write-through data cache (on a page per page basis).
 - Supports all PowerPC memory coherency modes.
 - Non-blocking instruction and data cache (one outstanding miss under hits).
 - No snooping of instruction cache.
- Memory management unit
 - 128 entry, 2-way set associative instruction TLB.
 - 128 entry, 2-way set associative data TLB.
 - Hardware reload for TLB's.
 - 4 instruction BAT's and 4 data BATs.
 - Virtual memory support for up to 4 exabytes (2^{52}) virtual memory.
 - Real memory support for up to 4 gigabytes (2^{32}) of physical memory.
- Level 2 (L2) cache interface (Not available on the 740)
 - Internal L2 cache controller and 4K-entry tags; external data SRAMs.
 - 256K, 512K, and 1 Mbyte 2-way set associative L2 cache support.
 - Copy-back or write-through data cache (on a page basis, or for all L2).
 - 64-byte (256K/512K) and 128-byte (1-Mbyte) sectored line size.
 - Supports flow-through (reg-buf) synchronous burst SRAMs, pipelined (reg-reg) synchronous burst SRAMs, and pipelined (reg-reg) late-write synchronous burst SRAMs.
 - Design supports Core-to-L2 frequency divisors of $\div 1$, $\div 1.5$, $\div 2$, $\div 2.5$, and $\div 3$; however, this specification supports the L2 frequency range specified in Section "L2 Clock AC Specifications," on page 16. For higher L2 frequencies not supported in this document, please contact your IBM marketing representative.



- Bus interface
 - Compatible with 60x processor interface.
 - 32-bit address bus.
 - 64-bit data bus (can be operated in 32-bit data bus mode).
 - Bus-to-core frequency multipliers of 2x, 2.5x, 3x, 3.5x, 4x, 4.5x, 5x, 5.5x, 6x, 6.5x, 7x, 7.5x, and 8x
- Integrated power management
 - Low-power 2.0/3.3V design.
 - Three static power saving modes: doze, nap, and sleep.
 - Automatic dynamic power reduction when internal functional units are idle.
- Integrated Thermal Management Assist Unit
 - On-chip thermal sensor and control logic.
 - Thermal Management Interrupt for software regulation of junction temperature.
- Testability
 - LSSD scan design.
 - JTAG interface.
- Reliability and serviceability—Parity checking on 60x and L2 cache buses

General Parameters

The following list provides a summary of the general parameters of the 750.

Technology	0.20 μ m CMOS (general lithography), six-layer copper metallization 0.12 \pm 0.04 μ m L _{eff}
Die Size	5.14mm x 7.78mm (40mm ²)
Transistor count	6.35 million
Logic design	Fully-static
Package	740: Surface mount 21x21mm, 255-lead ceramic ball grid array (CBGA) 750: Surface mount 25x25mm, 360-lead ceramic ball grid array (CBGA)
PPC 740/PPC 750 core power supply	2v Nominal
I/O power supply	3.3V \pm 5%



Electrical and Thermal Characteristics

This section provides both AC and DC electrical specifications and thermal characteristics for the 750.

DC Electrical Characteristics

The tables in this section describe the DC electrical characteristics of the 750. The following table provides the absolute maximum ratings.

Absolute Maximum Ratings

Characteristic	Symbol	Value	Unit
Core supply voltage	V_{DD}	-0.3 to 2.5	V
PLL supply voltage	AV_{DD}	-0.3 to 2.5	V
L2 DLL supply voltage	$L2AV_{DD}$	-0.3 to 2.5	V
60x bus supply voltage	OV_{DD}	-0.3 to 3.6	V
L2 bus supply voltage	$L2OV_{DD}$	-0.3 to 3.6	V
Input voltage	V_{IN}	-0.3 to 3.6	V
Storage temperature range	T_{STG}	-55 to 150	°C

Note:

1. Functional and tested operating conditions are given in Table "Recommended Operating Conditions," below. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. **Caution:** V_{IN} must not exceed OV_{DD} by more than 0.3V at any time, including during power-on reset. This is a DC specification only. V_{IN} overshoot transients up to $OV_{DD}+1V$, and undershoots down to $GND-1V$ (both measured with the 740 in the circuit) are allowed for up to 5ns.
3. **Caution:** OV_{DD} must not exceed V_{DD}/AV_{DD} by more than 2.0V at any time during normal operation. On power up and power down, OV_{DD} is allowed to exceed V_{DD}/AV_{DD} by up to 3.3V for up to 20 ms.
4. **Caution:** V_{DD}/AV_{DD} must not exceed OV_{DD} by more than 0.4V during normal operation. On power up and power down, V_{DD}/AV_{DD} is allowed to exceed OV_{DD} by up to 1.0V for up to 20 ms.
- 5.

Recommended Operating Conditions

Characteristic	Symbol	Value	Unit	Notes
Core supply voltage	V_{DD}	2.0	V	1, 2
PLL supply voltage	AV_{DD}	V_{DD}	V	1
L2 DLL supply voltage	$L2AV_{DD}$	V_{DD}	V	1
60x bus supply voltage	OV_{DD}	3.135 to 3.465	V	1
L2 bus supply voltage	$L2OV_{DD}$	3.135 to 3.465	V	1
Input voltage	V_{IN}	GND to $OV_{DD}+.3V$	V	1
Die-junction temperature	T_J	-40 to 105	°C	1, 2

Note:

1. These are recommended and tested operating conditions. Proper device operation outside of these conditions is not guaranteed.
2. V_{DD} and T_J are specified by the Application Conditions designator in the part number. See the Part Number Key on Page 43 for more information.

Package Thermal Characteristics¹

Characteristic	Symbol	740	750	Unit
Thermal resistance, junction-to-case (top surface of die) typical	θ_{JC}	0.03	0.03	°C/W
Thermal resistance, junction-to-balls, typical	θ_{JB}	3.8 - 7.1 ²	3.8 - 7.6 ²	°C/W
Thermal resistance, junction-to-ambient, at air-flow, no heat sink, typical	50 FPM	16.0	15.1	°C/W
	100 FPM	15.4	16.4	°C/W
	150 FPM	14.9	14.2	°C/W
	200 FPM	14.4	13.7	°C/W
Package Size		21 x 21	25 x 25	mm ²
Die Size		5.12 x 7.78	5.12 x 7.78	mm ²

Note:

1. Refer to Section "Thermal Management Information," on page 39 for more information about thermal management.
2. 3.8 °C/W is theoretical θ_{JB} mounted to infinite heat sink. The larger number applies to module mounted to a 1.8 mm thick, 2P card using 1 oz. copper power/gnd planes, with effective area for heat transfer of 75mm x 75mm.

The 750 incorporates a thermal management assist unit (TAU) composed of a thermal sensor, digital-to-analog converter, comparator, control logic, and dedicated special-purpose registers (SPRs). See the 750 PPC Microprocessor User's Manual for more information on the use of this feature. Specifications for the thermal sensor portion of the TAU are found in the table below.

Thermal Sensor Specifications

See Table "Recommended Operating Conditions," on page 7, for operating conditions.

Num	Characteristic	Minimum	Maximum	Unit	Notes
1	Temperature range	0	128	°C	1
2	Comparator settling time	20	—	ms	2
3	Resolution	4	—	°C	3
4	Drift, all sources	—	.25	LSb	
5	Linearity, error over range	—	1	LSb	
6	Offset error, reducible	—	2	LSb	

Note:

1. The temperature is the junction temperature of the die. The thermal assist unit's (TAU) raw output does not indicate an absolute temperature, but it must be interpreted by software to derive the absolute junction temperature. For information on how to use and calibrate the TAU, contact your local IBM sales office. This specification reflects the temperature span supported by the design.
2. The comparator settling time value must be converted into the number of CPU clocks that need to be written into the THRM3 SPR.
3. This value is guaranteed by design and is not tested.



DC Electrical Specifications

See Section "Recommended Operating Conditions," on page 7, for operating conditions.

Characteristic	Symbol	Min	Max	Unit	Notes
Input high voltage (all inputs except SYSCLK)	V_{IH}	2.0	–	V	1,2
Input low voltage (all inputs except SYSCLK)	V_{IL}	–	0.8	V	
SYSCLK input high voltage	CV_{IH}	2.4	–	V	1, 4
SYSCLK input low voltage	CV_{IL}	–	0.4	V	4
Input leakage current, $V_{IN} = OV_{DD}$	I_{IN}	–	20	μA	1,2
Hi-Z (off state) leakage current, $V_{in} = OV_{DD}$	I_{TSL}	–	20	μA	1,2
Output high voltage, $I_{OH} = -6mA$	V_{OH}	2.4	–	V	
Output low voltage, $I_{OL} = 6mA$	V_{OL}	–	0.4	V	
Capacitance, $V_{IN} = 0 V$, $f = 1MHz$	C_{IN}	–	5.0	pF	2,3

Note:

1. For 60x bus signals, the reference is OV_{DD} , while $L2OV_{DD}$ is the reference for the L2 bus signals.
2. Excludes test signals LSSD_MODE, L1_TSTCLK, L2_TSTCLK, and IEEE 1149.1 signals.
3. Capacitance values are guaranteed by design and characterization, and are not tested.
4. SYSCLK input high and low voltage: I/O timings are measured using a "rail to rail" SYSCLK; I/O timing may be less favorable if SYSCLK does not travel from GND to OV_{DD} .



**PowerPC 740 and PowerPC 750 Embedded Microprocessor
IBM CMOS 0.20 um Copper Technology EMPPC740L and EMPPC750L**

Power Consumption for 740 and 750

See Table "Recommended Operating Conditions," on page 7, for operating conditions

	Processor CPU Frequency					Unit	Notes
	300	333	366	400	466		
Full-On Mode							
Typical	3.7	4.0	4.3	4.6	5.5	W	1, 3, 4, 5
Maximum	4.8	5.3	5.8	6.1	6.8	W	1,2,4,5
Doze Mode							
Maximum	1.7	1.7	1.8	1.9	2.1	W	1,2,5
Nap Mode							
Maximum	250	250	250	250	250	mW	1, 5
Sleep Mode							
Maximum	TBD	TBD	TBD	TBD	TBD	mW	1, 5

Note:

- These values apply for all valid 60x bus and L2 bus ratios. The values do not include I/O Supply Power (OV_{DD} and $L2OV_{DD}$) or PLL/DLL supply power (AV_{DD} and $L2AV_{DD}$). OV_{DD} and $L2OV_{DD}$ power is system dependent, but is typically <10% of V_{DD} power. Worst case power consumption for AV_{DD} = 15mW and $L2AV_{DD}$ = 15mW.
- Maximum power is measured in a system executing worst case benchmark sequences at:
 - $V_{DD} = AV_{DD} = L2V_{DD} = 2.1V$;
 - $OV_{DD} = L2OV_{DD} = 3.3V$;
 - $T_j = 105^\circ C$ (300, 333, 366 MHz);
85°C (400 MHz);
65°C (466 MHz).
- Typical power is an average value measured in a system executing typical applications and benchmark sequences at:
 - $V_{DD} = AV_{DD} = L2AV_{DD} = 2.0V$ (300, 333, 366, 400 MHz);
 - $V_{DD} = AV_{DD} = L2AV_{DD} = 2.05V$ (466 MHz);
 - $OV_{DD} = L2OV_{DD} = 3.3V$;
 - $T_j = 45^\circ C$.
- Power dissipation is reduced approximately .1W per 10 degree C reduction in T_j .
- Guaranteed by design and characterization, and is not tested.

AC Electrical Characteristics

This section provides the AC electrical characteristics for the 750. After fabrication, parts are sorted by maximum processor core frequency as shown in the Section “Clock AC Specifications,” on page 11, and tested for conformance to the AC specifications for that frequency. The processor core frequency is determined by the bus (SYSCLK) frequency and the settings of the PLL_CFG(0-3) signals. Parts are sold by maximum processor core frequency; see Section “Ordering Information,” on page 45.

Clock AC Specifications

The following table provides the clock AC timing specifications as defined in Figure 2.

Clock AC Timing Specifications

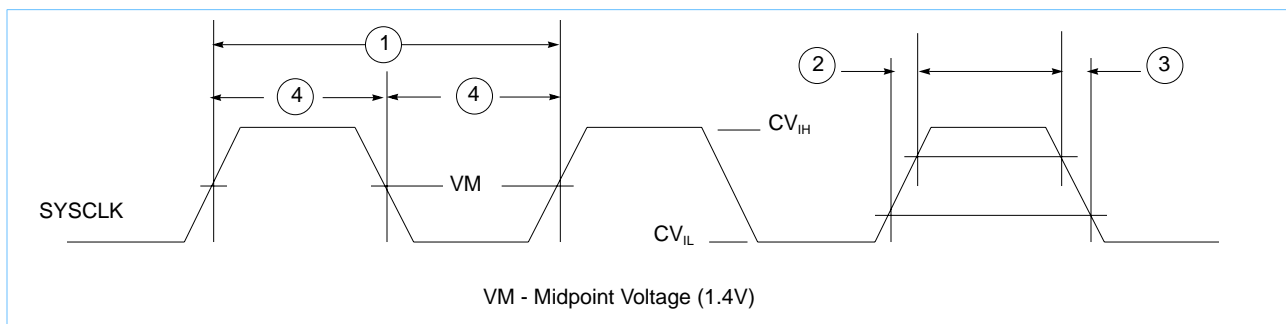
See Table “Recommended Operating Conditions,” on page 7, for operating conditions.

Num	Characteristic	300MHz		333MHz		366MHz		400MHz		466MHz		Unit	Notes
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
	Processor frequency	250	300	250	333	250	366	250	400	250	466	MHz	
	SYSCLK frequency	25	100	25	100	25	100	31	100	31	100	MHz	1
1	SYSCLK cycle time	10	40	10	40	12	40	10	32	10	32	ns	
2,3	SYSCLK rise and fall time	–	2.0	–	2.0	–	2.0	–	2.0	–	2.0	ns	2,3
4	SYSCLK duty cycle measured at 1.4 V	40	60	40	60	40	60	40	60	40	60	%	3
	SYSCLK jitter	–	±150	–	±150	–	±150	–	±150	–	±150	ps	4,3
	Internal PLL relock time	–	100	–	100	–	100	–	100	–	100	µs	5

Note:

1. Caution: The SYSCLK frequency and the PLL_CFG[0-3] settings must be chosen such that the resulting SYSCLK (bus) frequency, and CPU (core) frequency do not exceed their respective maximum or minimum operating frequencies. Refer to the PLL_CFG[0-3] signal description in Section “PLL Configuration,” on page 35 for valid PLL_CFG[0-3] settings.
2. Rise and fall times for the SYSCLK input are measured from 0.4 to 2.4V.
3. Timing is guaranteed by design and characterization, and is not tested.
4. The total input jitter (short term and long term combined) must be under ±150ps.
5. Relock timing is guaranteed by design and characterization, and is not tested. PLL-relock time is the maximum amount of time required for PLL lock after a stable V_{DD} and SYSCLK are reached during the power-on reset sequence. This specification also applies when the PLL has been disabled and subsequently re-enabled during sleep mode. Also note that HRESET must be held asserted for a minimum of 255 bus clocks after the PLL-relock time during the power-on reset sequence.

Figure 2. SYSCLK Input Timing Diagram





60x Bus Input AC Specifications

The following table provides the 60X bus input AC timing specifications for the 750 as defined in Figure 3 and Figure 4. Input timing specifications for the L2 bus are provided in Section, "L2 Bus Input AC Specifications" on page 18.

60X Bus Input Timing Specifications¹

See Table "Recommended Operating Conditions," on page 7, for operating conditions.

Num	Characteristic	300,333, 366, 400, 466MHz		Unit	Notes
		Minimum	Maximum		
10a	Address/Data/Transfer Attribute Inputs Valid to SYSCLK (Input Setup)	2.5	—	ns	2
10b	All Other Inputs Valid to SYSCLK (Input Setup)	2.5	—	ns	3
10c	Mode Select Input Setup to HRESET (DRTRY, TLBISYNC)	8	—	t _{sysclk}	4,5,6,7
11a	SYSCLK to Address/Data/Transfer Attribute Inputs Invalid (Input Hold)	0.6	—	ns	2
11b	SYSCLK to All Other Inputs Invalid (Input Hold)	0.6	—	ns	3
11c	HRESET to mode select input hold (DRTRY, TLBISYNC)	0	—	ns	4,6,7

Note:

- Input specifications are measured from the midpoint voltage (1.4V) of the signal in question to the midpoint voltage of the rising edge of the input SYSCLK. Input and output timings are measured at the pin (see Figure 3).
- Address/Data Transfer Attribute inputs are composed of the following—A[0-31], AP[0-3], TT[0-4], TBST, TSIZ[0-2], GBL, DH[0-31], DL[0-31], DP[0-7].
- All other signal inputs are composed of the following—TS, ABB, DBB, ARTRY, BG, AACK, DBG, DBWO, TA, DRTRY, TEA, DBDIS, TBEN, QACK, TLBISYNC.
- The setup and hold time is with respect to the rising edge of HRESET (see Figure 4).
- t_{sysclk} is the period of the external clock (SYSCLK) in nanoseconds (ns). The numbers given in the table must be multiplied by the period of SYSCLK to compute the actual time duration (in ns) of the parameter in question.
- These values are guaranteed by design, and are not tested.
- This specification is for configuration mode select only. Also note that the HRESET must be held asserted for a **minimum of 255 bus clocks** after the PLL re-lock time during the power-on reset sequence.

Figure 3. Input Timing Diagram

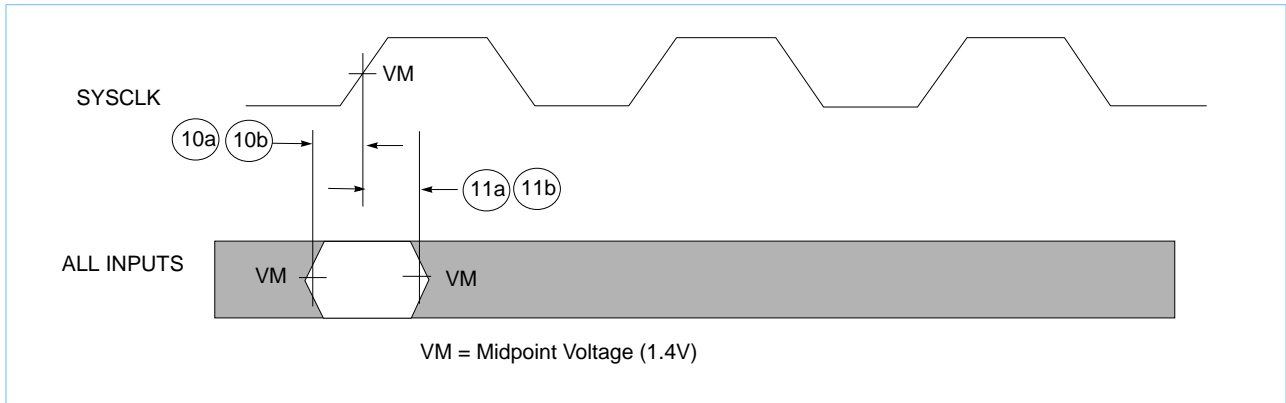
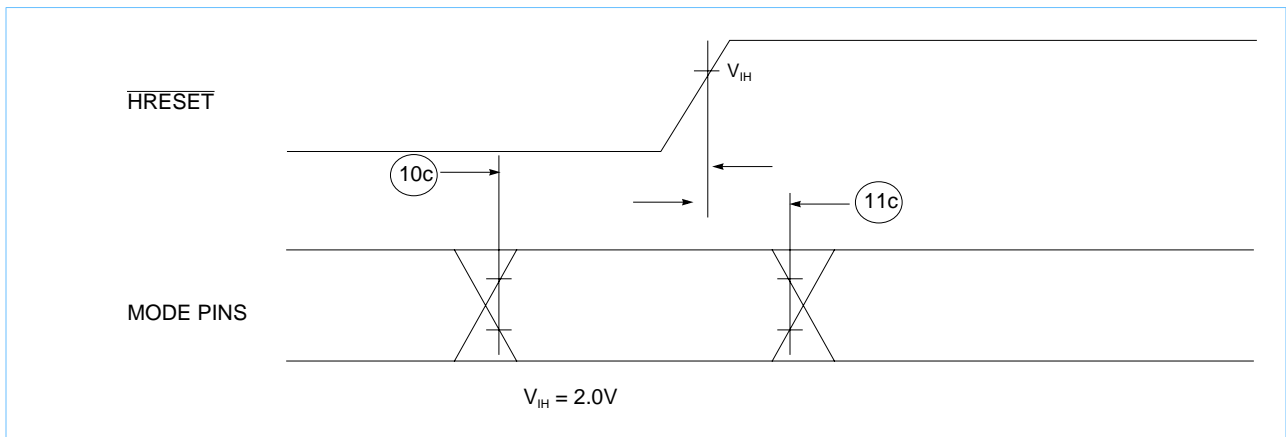


Figure 4. Mode Select Input Timing Diagram



60x Bus Output AC Specifications

The following table provides the 60x bus output AC timing specifications for the 750 as defined in Figure 5. Output timing specification for the L2 bus are provided in the Section "L2 Bus Output AC Specifications," on page 19.

60X Bus Output AC Timing Specifications for the 750¹

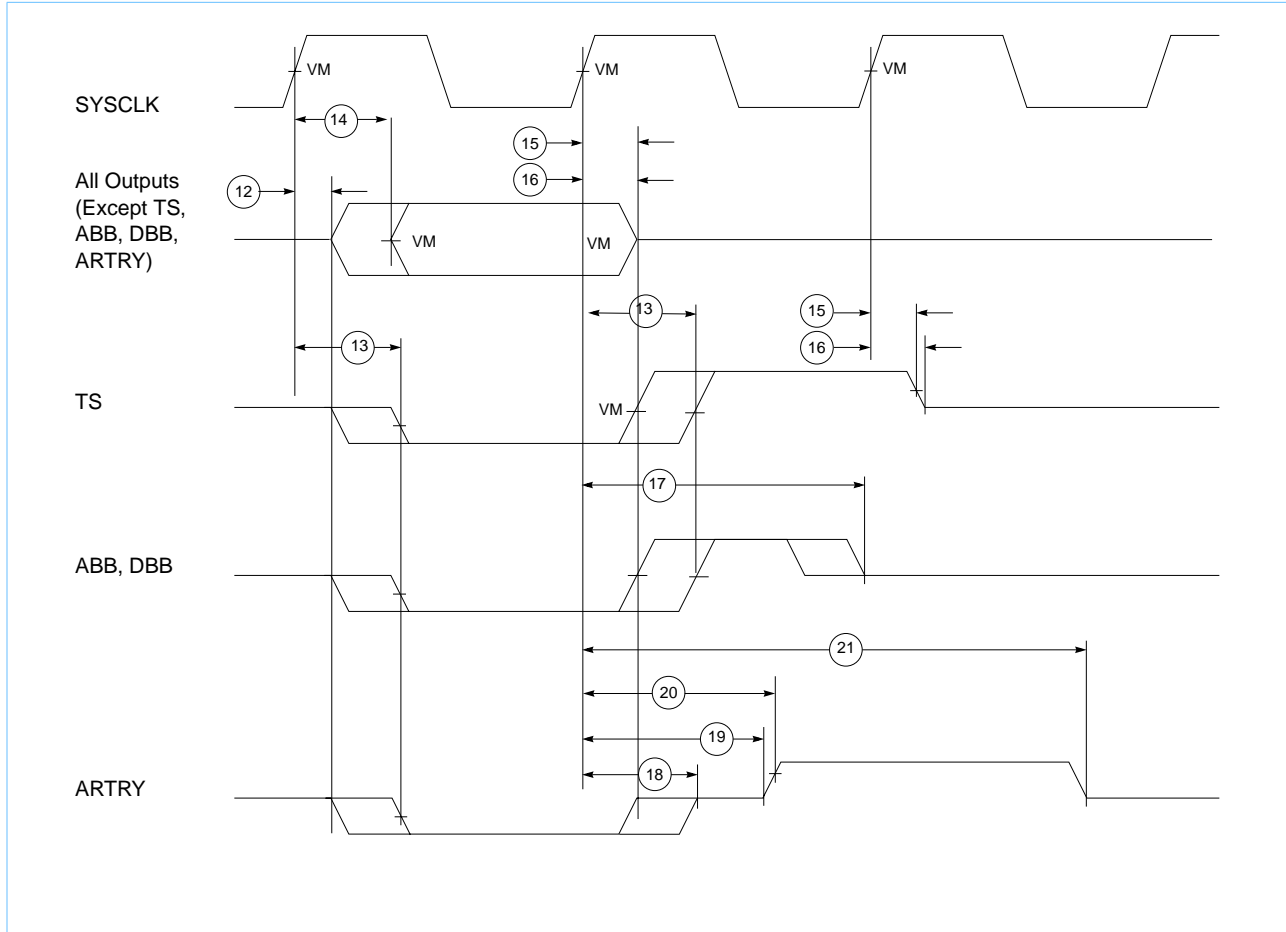
See Table "Recommended Operating Conditions," on page 7 for operating conditions, $C_L = 50\text{pF}^2$

Num	Characteristic	300, 333, 366, 400, 466 MHz		Unit	Notes
		Minimum	Maximum		
12	SYSClk to Output Driven (Output Enable Time)	0.5		ns	8
13	SYSClk to Output Valid ($\overline{\text{TS}}$, $\overline{\text{ABB}}$, $\overline{\text{ARTRY}}$, $\overline{\text{DBB}}$, and $\overline{\text{TBST}}$)	–	4.5	ns	5
14	SYSClk to all other Output Valid (all except $\overline{\text{TS}}$, $\overline{\text{ABB}}$, $\overline{\text{ARTRY}}$, $\overline{\text{DBB}}$, and $\overline{\text{TBST}}$)	–	5.0	ns	5
15	SYSClk to Output Invalid (Output Hold) (optional: L2_TSTCLK = GND)	1.0 1.2		ns	3, 8, 9
16	SYSClk to Output High Impedance (all signals except $\overline{\text{ABB}}$, $\overline{\text{ARTRY}}$, and $\overline{\text{DBB}}$)	–	6.0	ns	8
17	SYSClk to $\overline{\text{ABB}}$ and $\overline{\text{DBB}}$ high impedance after precharge	–	1.0	t_{SYSClk}	4, 6, 8
18	SYSClk to $\overline{\text{ARTRY}}$ high impedance before precharge	–	5.5	ns	8
19	SYSClk to $\overline{\text{ARTRY}}$ precharge enable	$0.2 \times t_{\text{SYSClk}} + 1.0$		ns	3, 4, 7
20	Maximum delay to $\overline{\text{ARTRY}}$ precharge		1	t_{SYSClk}	4, 7
21	SYSClk to $\overline{\text{ARTRY}}$ high impedance after precharge		2	t_{SYSClk}	4, 7, 8

Note:

- All output specifications are measured from the midpoint voltage (1.4V) of the rising edge of SYSClk to the midpoint voltage of the signal in question. Both input and output timings are measured at the pin.
- All maximum timing specifications assume $C_L = 50\text{pF}$.
- This minimum parameter assumes $C_L = 0\text{pF}$.
- t_{SYSClk} is the period of the external bus clock (SYSClk) in nanoseconds (ns). The numbers given in the table must be multiplied by the period of SYSClk to compute the actual time duration of the parameter in question.
- Output signal transitions from GND to 2.0V or OV_{DD} to 0.8V.
- Nominal precharge width for $\overline{\text{ABB}}$ and $\overline{\text{DBB}}$ is $0.5 t_{\text{SYSClk}}$.
- Nominal precharge width for $\overline{\text{ARTRY}}$ is $1.0 t_{\text{SYSClk}}$.
- Guaranteed by design and characterization, and not tested.
- For extra output hold, L2_TSTCLK may be tied to ground. Otherwise L2_TSTCLK should be tied to OV_{DD} .

Figure 5. Output Timing Diagram



L2 Clock AC Specifications

The following table provides the L2CLK output AC timing specifications for the 750 as defined in Figure 6.

L2CLK Output AC Timing Specifications

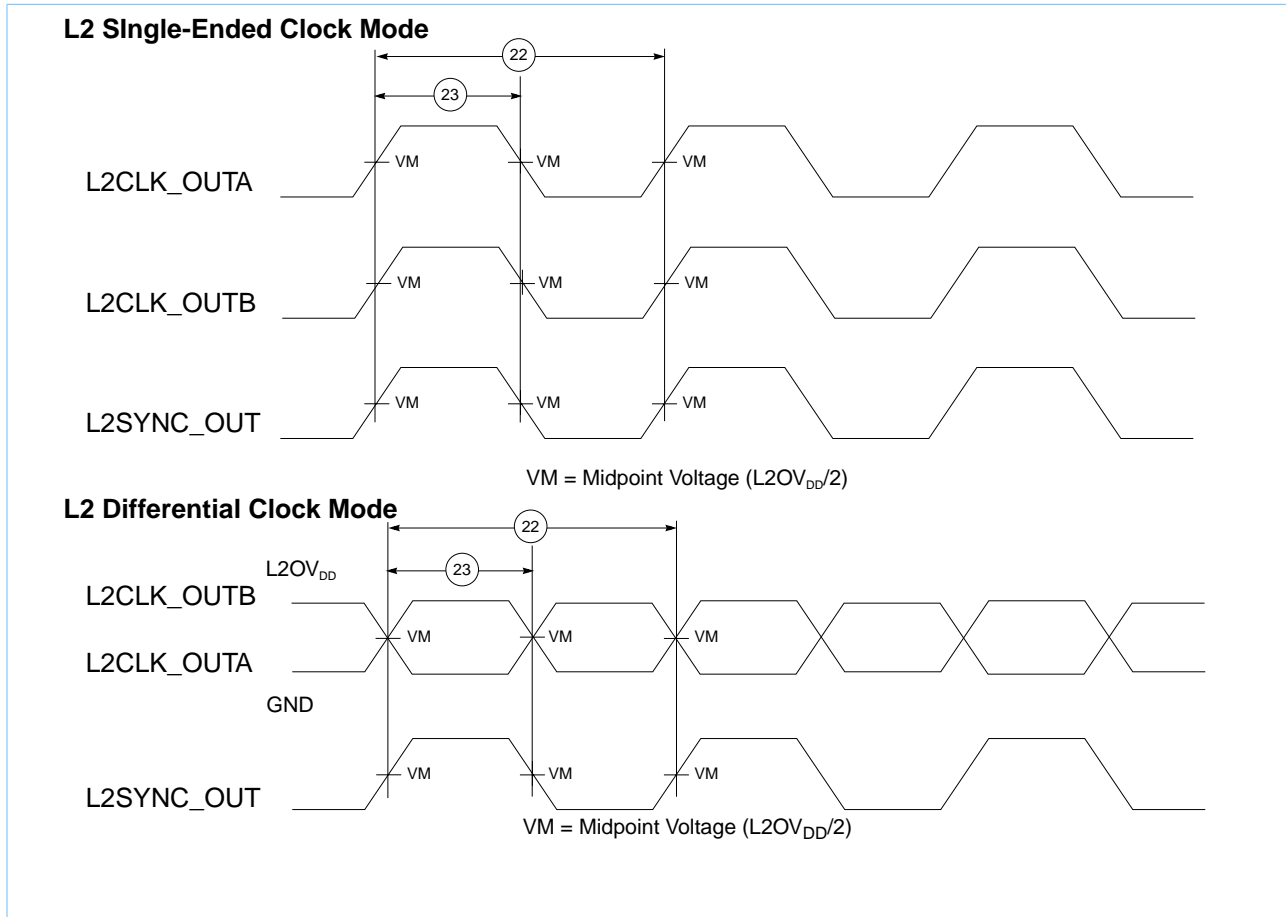
See Table "Recommended Operating Conditions," on page 7, for operating conditions.

Num	Characteristic	Min	Max	Unit	Notes
	L2CLK frequency	80	233	MHz	1, 4
22	L2CLK cycle time	4.3	12.5	ns	
23	L2CLK duty cycle	50		%	2
	Internal DLL-relock time	640	—	L2CLK	3

Note:

1. L2CLK outputs are L2CLKOUTA, L2CLKOUTB and L2SYNC_OUT pins. The internal design supports higher L2CLK frequencies; however, the L2 I/O drivers have been designed to support a 150MHz L2 bus loaded with 4 off-the-shelf pipelined synchronous burst SRAMs. Running the L2 bus beyond 150 MHz would require tightly coupled customized SRAMs or a multi-chip module (MCM) implementation. The L2CLK frequency to core frequency settings must be chosen such that the resulting L2CLK frequency and core frequency do not exceed their respective maximum or minimum operating frequencies. L2CLKOUTA and L2CLKOUTB must have equal loading.
2. The nominal duty cycle of the L2CLK is 50% measured at midpoint voltage.
3. The DLL re-lock time is specified in terms of L2CLKs. The number in the table must be multiplied by the period of L2CLK to compute the actual time duration in nanoseconds. Re-lock timing is guaranteed by design and characterization, and is not tested.
4. The L2CR [L2SL] bit should be set for L2CLK frequencies less than 110MHz.

Figure 6. L2CLK_OUT Output Timing Diagram



L2 Bus Input AC Specifications

The L2 bus input interface AC timing specifications are found in the following table. See Figure 7.

L2 Bus Input Interface AC Timing Specifications

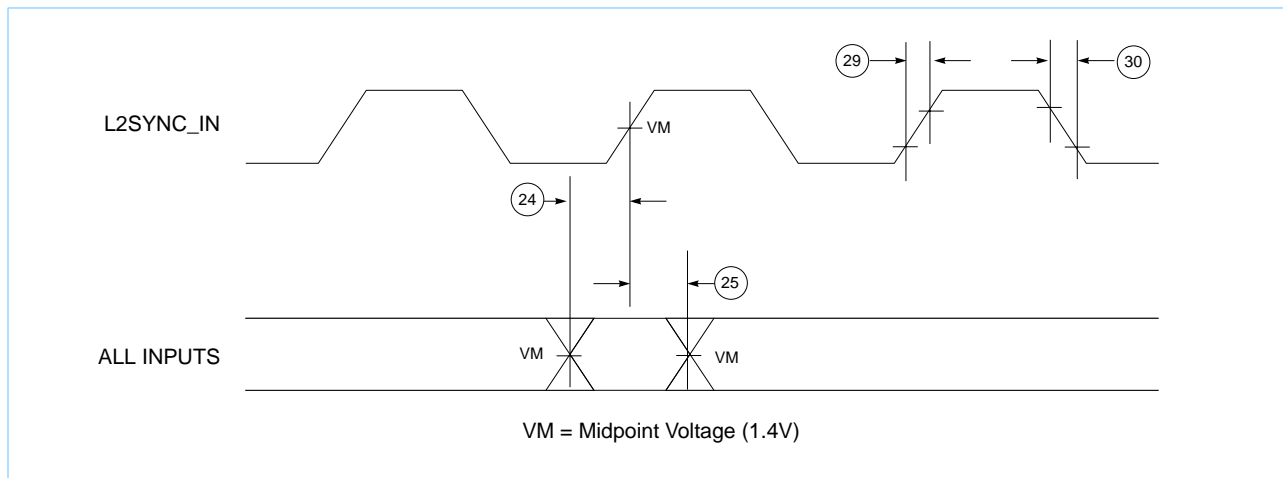
See Table “Recommended Operating Conditions,” on page 7, for operating conditions.

Num	Characteristic	Min	Max	Unit	Notes
29,30	L2SYNC_IN rise and fall time	—	1.0	ns	2,3
24	Data and parity input setup to L2SYNC_IN, 300, 333, 366 MHz processor sorts.	1.5	—	ns	1
24	Data and parity input setup to L2SYNC_IN, 400 MHz processor sort.	1.4	—	ns	1
24	Data and parity input setup to L2SYNC_IN, 466 MHz processor sort.	1.1	—	ns	1
25	L2SYNC_IN to data and parity input hold	0.5	—	ns	1

Note:

1. All input specifications are measured from the midpoint voltage (1.4V) of the signal in question to the midpoint voltage of the rising edge of the input L2SYNC_IN. Input timings are measured at the pins (see Figure 7).
2. Rise and fall times for the L2SYNC_IN input are measured from 0.4 to 2.4V.
3. Guaranteed by design and characterization, and not tested.

Figure 7. L2 Bus Input Timing Diagrams



L2 Bus Output AC Specifications

The following table provides the L2 bus output interface AC timing specifications for the 750 as defined in Figure 8.

L2 Bus Output Interface AC Timing Specifications¹

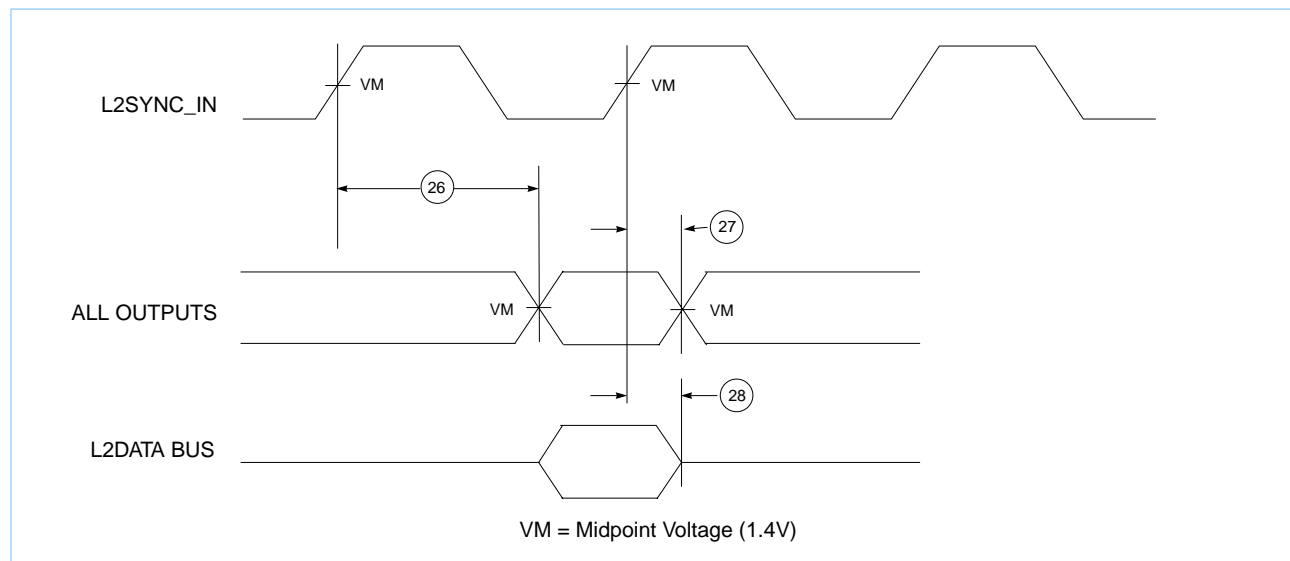
See Table "Recommended Operating Conditions," on page 7 for operating conditions, $C_L = 20\text{pF}^3$

Num	Characteristic	L2CR[14-15] is equivalent to:								Unit	Notes
		00 ²		01		10		11			
		Min	Max	Min	Max	Min	Max	Min	Max		
26	L2SYNC_IN to output valid, 300, 333, 366 MHz processor sorts.	—	3.2	—	3.7	—	Rsv ⁵	—	Rsv ⁵	ns	
26	L2SYNC_IN to output valid, 400 MHz processor sort.	—	3.0	—	3.5	—	Rsv ⁵	—	Rsv ⁵	ns	
26	L2SYNC_IN to output valid, 466 MHz processor sort.	—	2.6	—	3.1	—	Rsv ⁵	—	Rsv ⁵	ns	
27	L2SYNC_IN to output hold	0.5	—	1.0	—	Rsv ⁵	—	Rsv ⁵	—	ns	4,6
28	L2SYNC_IN to high impedance	—	3.0	—	4.0	—	Rsv ⁵	—	Rsv ⁵	ns	6

Note:

- All outputs are measured from the midpoint voltage (1.4v) of the rising edge of L2SYNC_IN to the midpoint voltage of the signal in question. The output timings are measured at the pins.
- The outputs are valid for both single-ended and differential L2CLK modes. For flow-through and pipelined reg-reg synchronous burst SRAMs, L2CR[14-15] = 00 is recommended. For pipelined late-write synchronous burst SRAMs, L2CR[14-15] = 01 is recommended.
- All maximum timing specifications assume $C_L = 20\text{pF}$.
- This measurement assumes $C_L = 5\text{pF}$.
- Reserved for future use.
- Guaranteed by design and characterization, and not tested.

Figure 8. L2 Bus Output Timing Diagrams



IEEE 1149.1 AC Timing Specifications

The table below provides the IEEE 1149.1 (JTAG) AC timing specifications as defined in Figure 9, Figure 10, Figure 11, and Figure 12. The five JTAG signals are; TDI, TDO, TMS, TCK, and $\overline{\text{TRST}}$.

JTAG AC Timing Specifications (Independent of SYSCLK)

See Table "Recommended Operating Conditions," on page 7 for operating conditions, $C_L = 50\text{pF}$.

Num	Characteristic	Min	Max	Unit	Notes
	TCK frequency of operation	0	25	MHz	
1	TCK cycle time	40	—	ns	
2	TCK clock pulse width measured at 1.4V	15	—	ns	
3	TCK rise and fall times	0	2	ns	4
4	spec obsolete, intentionally omitted				
5	$\overline{\text{TRST}}$ assert time	25	—	ns	1
6	Boundary-scan input data setup time	4	—	ns	2
7	Boundary-scan input data hold time	16	—	ns	2
8	TCK to output data valid	4	20	ns	3, 5
9	TCK to output high impedance	3	19	ns	3, 4
10	TMS, TDI data setup time	0	—	ns	
11	TMS, TDI data hold time	15	—	ns	
12	TCK to TDO data valid	2.5	12	ns	5
13	TCK to TDO high impedance	3	9	ns	4

Note:

1. $\overline{\text{TRST}}$ is an asynchronous level sensitive signal. Guaranteed by design.
2. Non-JTAG signal input timing with respect to TCK.
3. Non-JTAG signal output timing with respect to TCK.
4. Guaranteed by characterization and not tested.
5. Minimum spec guaranteed by characterization and not tested.

Figure 9. JTAG Clock Input Timing Diagram

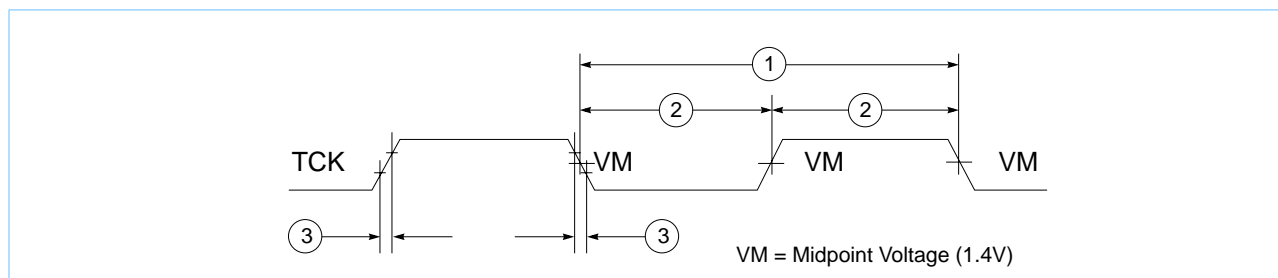


Figure 10. TRST Timing Diagram

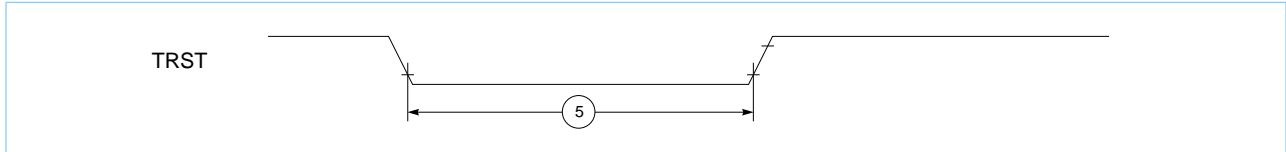


Figure 11. Boundary-Scan Timing Diagram

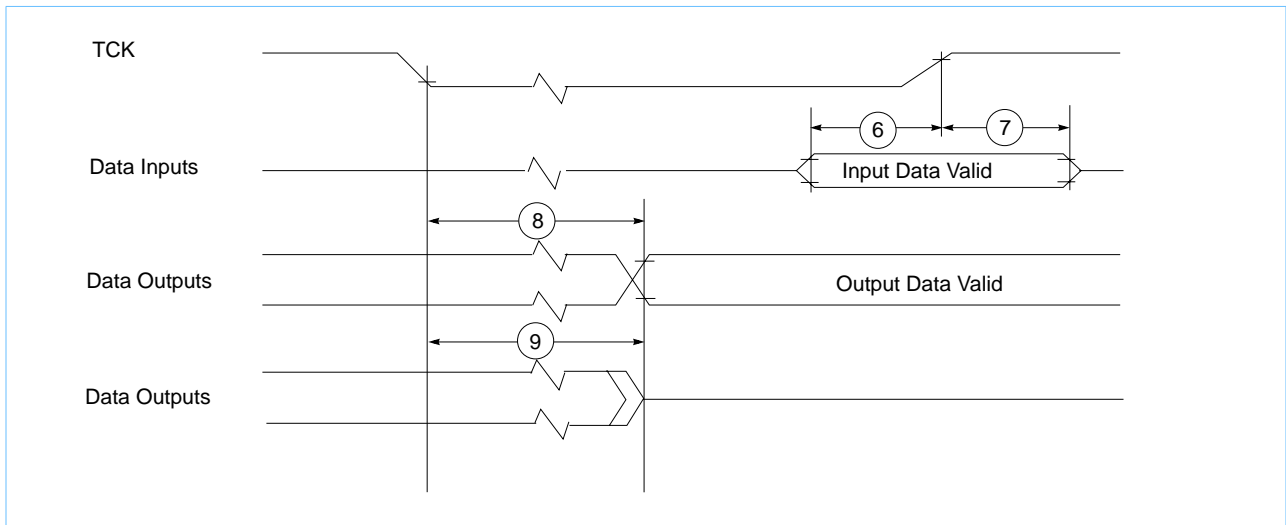
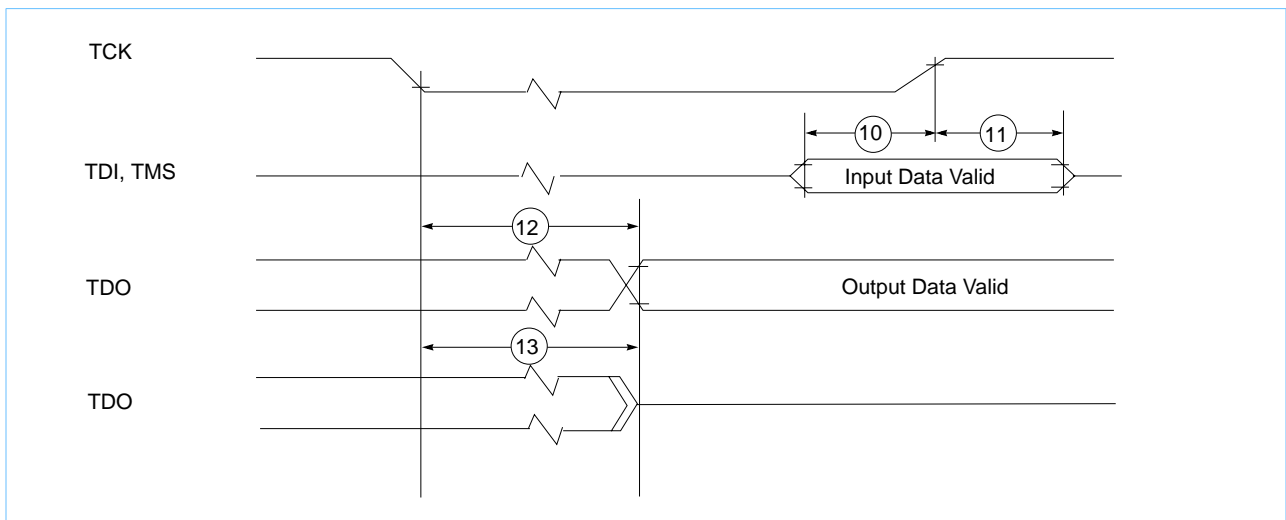


Figure 12. Test Access Port Timing Diagram

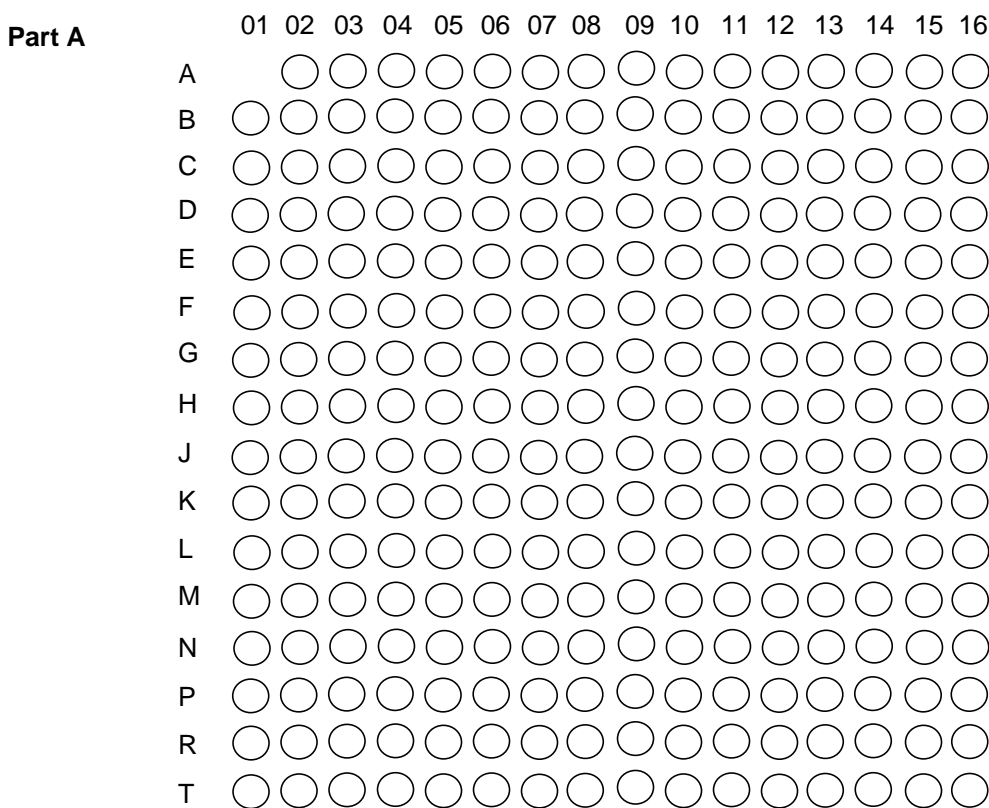


PowerPC 740 Microprocessor Pin Assignments

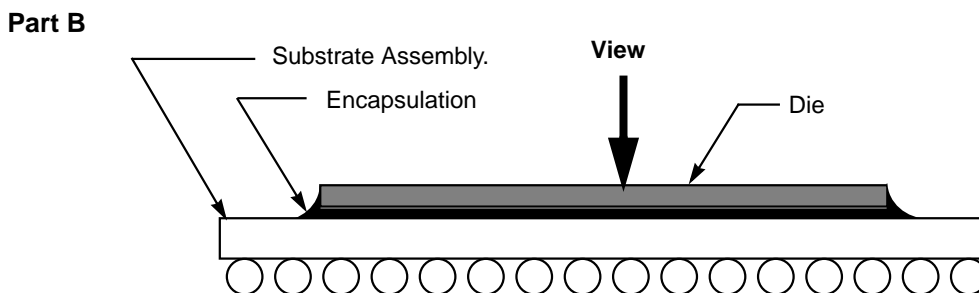
The following sections contain the pinout diagrams for the PowerPC 740, a 255 pin ceramic ball grid array (BGA) package.

Figure 13 (in part A) shows the pinout of the 255 CBGA package as viewed from the top surface. Part B shows the side profile of the 255 CBGA package to indicate the direction of the top surface view.

Figure 13. Pinout of the PowerPC 740 BGA Package as Viewed from the Top Surface



Not to Scale





PowerPC 740 Microprocessor Pinout Listings

the “Pinout Listing for the 255 CBGA Package” Table on page 23 provides the pinout listing for the 255 CBGA package (the PowerPC 740).

Pinout Listing for the 255 CBGA Package

Signal Name	Pin Number	Active	I/O
A0-A31	C16, E04, D13, F02, D14, G01, D15, E02, D16, D04, E13, GO2, E15, H01, E16, H02, F13, J01, F14, J02, F15, H03, F16, F04, G13, K01, G15, K02, H16, M01, J15, P01	High	I/O
\overline{AACK}	L02	Low	Input
\overline{ABB}	K04	Low	I/O
AP0-AP3	C01, B04, B03, B02	High	I/O
\overline{ARTRY}	J04	Low	I/O
AVDD	A10	—	—
BG	L01	Low	Input
BR	B06	Low	Output
\overline{CI}	E01	Low	Output
$\overline{CKSTP_IN}$	D08	Low	Input
$\overline{CKSTP_OUT}$	A06	Low	Output
CLK_OUT	D07	—	Output
DBB	J14	Low	I/O
DBG	N01	Low	Input
DBDIS	H15	Low	Input
\overline{DBWO}	G04	Low	Input
DH0-DH31	P14, T16, R15, T15, R13, R12, P11, N11, R11, T12, T11, R10, P09, N09, T10, R09, T09, P08, N08, R08, T08, N07, R07, T07, P06, N06, R06, T06, R05, N05, T05, T04	High	I/O
DL0-DL31	K13, K15, K16, L16, L15, L13, L14, M16, M15, M13, N16, N15, N13, N14, P16, P15, R16, R14, T14, N10, P13, N12, T13, P03, N03, N04, R03, T01, T02, P04, T03, R04	High	I/O
DP0-DP7	M02, L03, N02, L04, R01, P02, M04, R02	High	I/O
\overline{DRTRY}	G16	Low	Input
\overline{GBL}	F01	Low	I/O
GND	C05, C12, E03, E06, E08, E09, E11, E14, F05, F07, F10, F12, G06, G08, G09, G11, H05, H07, H10, H12, J05, J07, J10, J12, K06, K08, K09, K11, L05, L07, L10, L12, M03, M06, M08, M09, M11, M14, P05, P12	—	—

Pinout Listing for the 255 CBGA Package (cont.)

Signal Name	Pin Number	Active	I/O
HRESET	A07	Low	Input
INT	B15	Low	Input
L1_TSTCLK ¹	D11	High	Input
L2_TSTCLK ¹	D12	High	Input
LSSD_MODE ¹	B10	Low	Input
MCP	C13	Low	Input
NC (No-Connect)	B07, B08, C03, C06, C08, D05, D06, H04, J16, A04, A05, A02, A03, B01, B05	—	—
OVDD	C07, E05, E07, E10, E12, G03, G05, G12, G14, K03, K05, K12, K14, M05, M07, M10, M12, P07, P10	—	—
PLL_CFG[0-3]	A08, B09, A09, D09	High	Input
QACK	D03	Low	Input
QREQ	J03	Low	Output
RSRV	D01	Low	Output
SMI	A16	Low	Input
SRESET	B14	Low	Input
SYSCLK	C09	—	Input
TA	H14	Low	Input
TBEN	C02	High	Input
TBST	A14	Low	I/O
TCK	C11	High	Input
TDI	A11	High	Input
TDO	A12	High	Output
TEA	H13	Low	Input
TLBISYNC	C04	Low	Input
TMS	B11	High	Input
TRST	C10	Low	Input
TS	J13	Low	I/O
TSIZ0-TSIZ2	A13, D10, B12,	High	Output
TT0-TT4	B13, A15, B16, C14, C15	High	I/O
WT	D02	Low	Output



Pinout Listing for the 255 CBGA Package (cont.)

Signal Name	Pin Number	Active	I/O
VDD ²	F06, F08, F09, F11, G07, G10, H06, H08, H09, H11, J06, J08, J09, J11, K07, K10, L06, L08, L09, L11	—	—
VOLTDET ³	F03	Low	Output

Note:

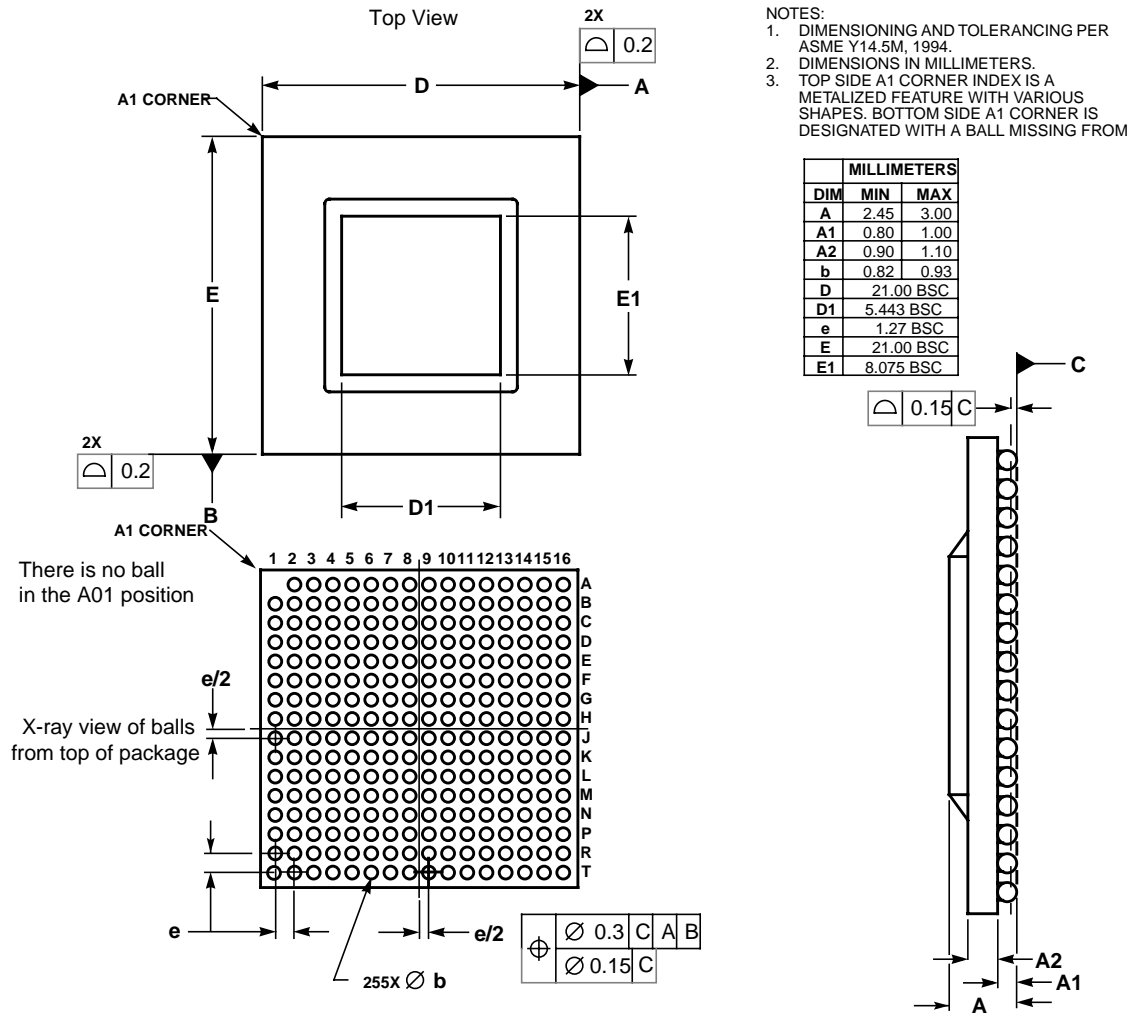
1. These are test signals for factory use only and must be pulled up to OVdd for normal operation.
2. OVdd inputs supply power to the I/O drivers and Vdd inputs supply power to the processor core.
3. Internally tied to GND in the 255 CBGA package to indicate to the power supply that a low-voltage processor is present. This is NOT a supply pin.

PowerPC 740 Package

Package Type	Ceramic Ball Grid Array (CBGA)
Package outline	21 x 21mm
Interconnects	255 (16 x 16 ball array - 1)
Pitch	1.27mm (50mil)
Minimum module height	2.45mm
Maximum module height	3.00mm
Ball diameter	0.89mm (35mil)

Mechanical Dimensions of the 255 CBGA Package

Figure 14. Mechanical Dimensions and Bottom Surface Nomenclature of the 255 CBGA Package

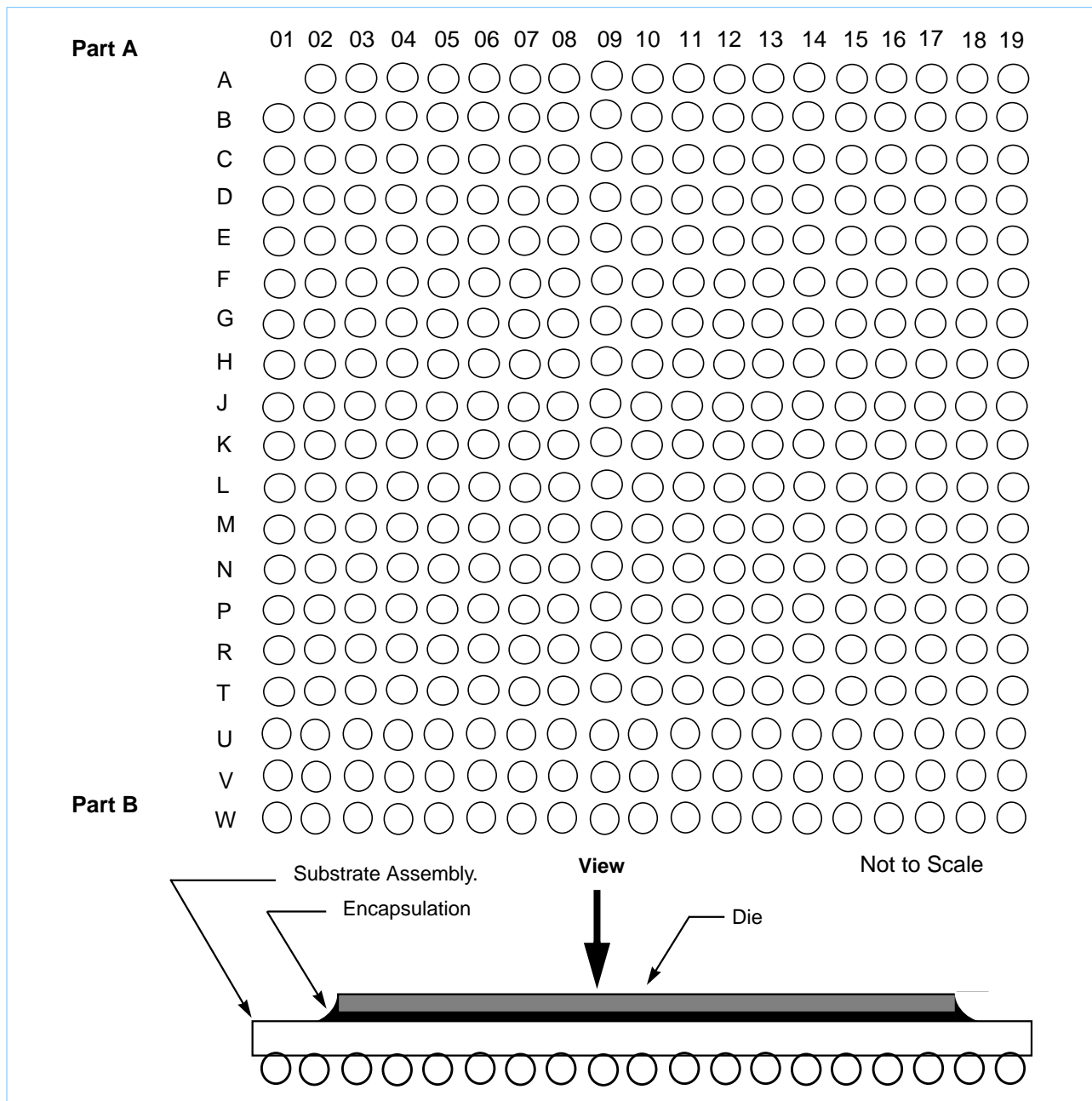


PowerPC 750 Microprocessor Pin Assignments

The following sections contain the pinout diagrams for the 750. IBM offers a ceramic ball grid array 360 CBGA packages.

Figure 15 (in part A) shows the pinout of the 360 CBGA package as viewed from the top surface. Part B shows the side profile of the 360 CBGA package to indicate the direction of the top surface view.

Figure 15. Pinout of the 750 360 CBGA Package as Viewed from the Top Surface





Pinout Listing for the 360 CBGA package

Signal Name	Pin Number	Active	I/O
A0-A31	A13, D2, H11, C1, B13, F2, C13, E5, D13, G7, F12, G3, G6, H2, E2, L3, G5, L4, G4, J4, H7, E1, G2, F3, J7, M3, H3, J2, J6, K3, K2, L2	High	I/O
AACK	N3	Low	Input
ABB	L7	Low	I/O
AP0-AP3	C4, C5, C6, C7	High	I/O
ARTRY	L6	Low	I/O
AVDD	A8	—	—
BG	H1	Low	Input
BR	E7	Low	Output
BVSEL	W01 ⁶	—	Input
CKSTP_OUT	D7	Low	Output
CI	C2	Low	Output
CKSTP_IN	B8	Low	Input
CLKOUT	E3	--	Output
DBB	K5	Low	I/O
DBDIS	G1	Low	Input
DBG	K1	Low	Input
DBWO	D1	Low	Input
DH0-DH31	W12, W11, V11, T9, W10, U9, U10, M11, M9, P8, W7, P9, W9, R10, W6, V7, V6, U8, V9, T7, U7, R7, U6, W5, U5, W4, P7, V5, V4, W3, U4, R5	High	I/O
DL0-DL31	M6, P3, N4, N5, R3, M7, T2, N6, U2, N7, P11, V13, U12, P12, T13, W13, U13, V10, W8, T11, U11, V12, V8, T1, P1, V1, U1, N1, R2, V3, U3, W2	High	I/O
DP0-DP7	L1, P2, M2, V2, M1, N2, T3, R1	High	I/O
DRTRY	H6	Low	Input
GBL	B1	Low	I/O
GND	D10, D14, D16, D4, D6, E12, E8, F4, F6, F10, F14, F16, G9, G11, H5, H8, H10, H12, H15, J9, J11, K4, K6, K8, K10, K12, K14, K16, L9, L11, M5, M8, M10, M12, M15, N9, N11, P4, P6, P10, P14, P16, R8, R12, T4, T6, T10, T14, T16	—	—

Note:

1. These are test signals for factory use only and must be pulled up to OV_{DD} for normal machine operation.
2. OV_{DD} inputs supply power to the I/O drivers and V_{DD} inputs supply power to the processor core.
3. Internally tied to L2OV_{DD} in the 750 360 CBGA package. This is NOT a supply pin.
4. These pins are reserved for potential future use as additional L2 address pins.
5. L2_TSTCLK may be tied to ground for normal machine operation, if extra 60x bus output hold is required on all 60x bus signals. See Table "60X Bus Output AC Timing Specifications for the 750¹," on page 14, spec 15.
6. These pins are no connects on dd2.x and have no function. They will be added to dd3.x to select voltage levels for the L2 bus (A19) and the rest of the I/O (W01). Leaving the pin unconnected will select the normal supply value. Connecting these pins to HRESET# or ground on dd3.x will select lower voltage supply ranges.



**PowerPC 740 and PowerPC 750 Embedded Microprocessor
IBM CMOS 0.20 um Copper Technology EMPPC740L and EMPPC750L**

Pinout Listing for the 360 CBGA package (cont.)

Signal Name	Pin Number	Active	I/O
HRESET	B6	Low	Input
INT	C11	Low	Input
L1_TSTCLK ¹	F8	High	Input
L2ADDR[0-16]	L17, L18, L19, M19, K18, K17, K15, J19, J18, J17, J16, H18, H17, J14, J13, H19, G18	High	Output
L2AVDD	L13	—	—
L2CE	P17	Low	Output
L2CLKOUTA	N15	—	Output
L2CLKOUTB	L16	—	Output
L2DATA[0-63]	U14, R13, W14, W15, V15, U15, W16, V16, W17, V17, U17, W18, V18, U18, V19, U19, T18, T17, R19, R18, R17, R15, P19, P18, P13, N14, N13, N19, N17, M17, M13, M18, H13, G19, G16, G15, G14, G13, F19, F18, F13, E19, E18, E17, E15, D19, D18, D17, C18, C17, B19, B18, B17, A18, A17, A16, B16, C16, A14, A15, C15, B14, C14, E13	High	I/O
L2DP[0-7]	V14, U16, T19, N18, H14, F17, C19, B15	High	I/O
L2OVDD	D15, E14, E16, H16, J15, L15, M16, P15, R14, R16, T15, F15	—	—
L2SYNC_IN	L14	—	Input
L2SYNC_OUT	M14	—	Output
L2_TSTCLK ^{1,5}	F7	High	Input
L2VSEL	A19 ⁶	—	Input
L2WE	N16	Low	Output
L2ZZ	G17	High	Output
LSSD_MODE ¹	F9	Low	Input
MCP	B11	Low	Input
NC (No-Connect)	B3, B4, B5, W19, K9, K11 ⁴ , K19 ⁴	—	—
OVDD ²	D5, D8, D12, E4, E6, E9, E11, F5, H4, J5, L5, M4, P5, R4, R6, R9, R11, T5, T8, T12	—	—
PLL_CFG[0-3]	A4, A5, A6, A7	High	Input
QACK	B2	Low	Input
QREQ	J3	Low	Output

Note:

1. These are test signals for factory use only and must be pulled up to OV_{DD} for normal machine operation.
2. OV_{DD} inputs supply power to the I/O drivers and V_{DD} inputs supply power to the processor core.
3. Internally tied to L2OV_{DD} in the 750 360 CBGA package. This is NOT a supply pin.
4. These pins are reserved for potential future use as additional L2 address pins.
5. L2_TSTCLK may be tied to ground for normal machine operation, if extra 60x bus output hold is required on all 60x bus signals. See Table "60X Bus Output AC Timing Specifications for the 750¹," on page 14, spec 15.
6. These pins are no connects on dd2.x and have no function. They will be added to dd3.x to select voltage levels for the L2 bus (A19) and the rest of the I/O (W01). Leaving the pin unconnected will select the normal supply value. Connecting these pins to HRESET# or ground on dd3.x will select lower voltage supply ranges.



Pinout Listing for the 360 CBGA package (cont.)

Signal Name	Pin Number	Active	I/O
RSRV	D3	Low	Output
SMI	A12	Low	Input
SRESET	E10	Low	Input
SYSCLK	H9	—	Input
TA	F1	Low	Input
TBEN	A2	High	Input
TBST	A11	Low	I/O
TCK	B10	High	Input
TDI	B7	High	Input
TDO	D9	High	Output
TEA	J1	Low	Input
TLBISYNC	A3	Low	Input
TMS	C8	High	Input
TRST	A10	Low	Input
TS	K7	Low	I/O
TSIZ0-TSIZ2	A9, B9, C9	High	Output
TT0-TT4	C10, D11, B12, C12, F11	High	I/O
WT	C3	Low	Output
VDD ²	G8, G10, G12, J8, J10, J12, L8, L10, L12, N8, N10, N12	—	—
VOLTDET ³	K13	High	Output

Note:

1. These are test signals for factory use only and must be pulled up to OV_{DD} for normal machine operation.
2. OV_{DD} inputs supply power to the I/O drivers and V_{DD} inputs supply power to the processor core.
3. Internally tied to $L2OV_{DD}$ in the 750 360 CBGA package. This is NOT a supply pin.
4. These pins are reserved for potential future use as additional L2 address pins.
5. $L2_TSTCLK$ may be tied to ground for normal machine operation, if extra 60x bus output hold is required on all 60x bus signals. See Table "60X Bus Output AC Timing Specifications for the 750¹," on page 14, spec 15.
6. These pins are no connects on dd2.x and have no function. They will be added to dd3.x to select voltage levels for the L2 bus (A19) and the rest of the I/O (W01). Leaving the pin unconnected will select the normal supply value. Connecting these pins to HRESET# or ground on dd3.x will select lower voltage supply ranges.

PowerPC 750 Package

Package Type	Ceramic Ball Grid Array (CBGA)
Package outline	25 x 25mm
Interconnects	360 (19 x 19 ball array - 1)
Pitch	1.27mm (50mil)
Minimum module height	2.65mm
Maximum module height	3.20mm
Ball diameter	0.89mm (35mil)

Mechanical Dimensions of the 360 CBGA Package

Figure 16 provides the mechanical dimensions and bottom surface nomenclature of the 360 CBGA package.

Figure 16. Mechanical Dimensions and Bottom Surface Nomenclature of the 360 CBGA Package

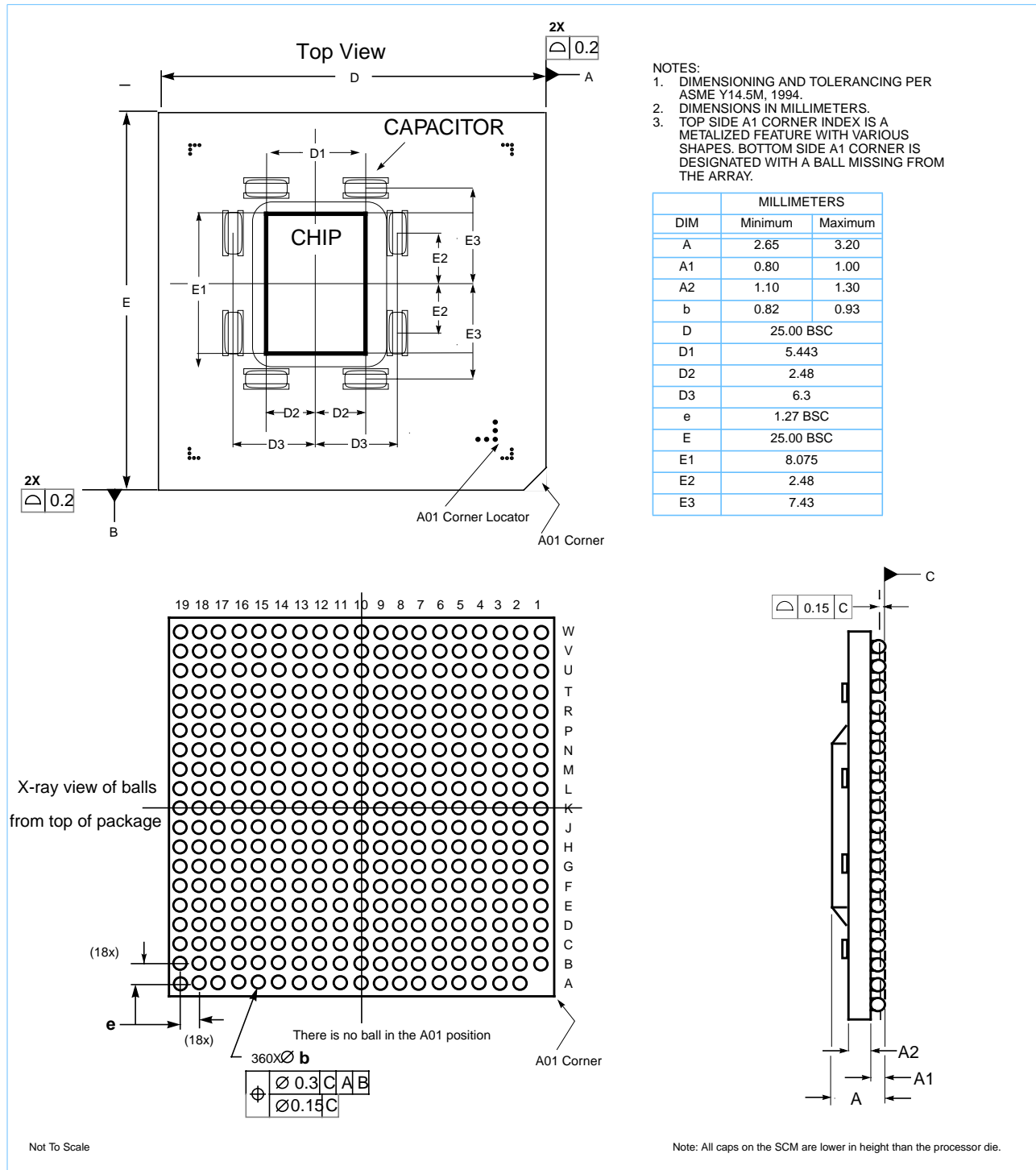
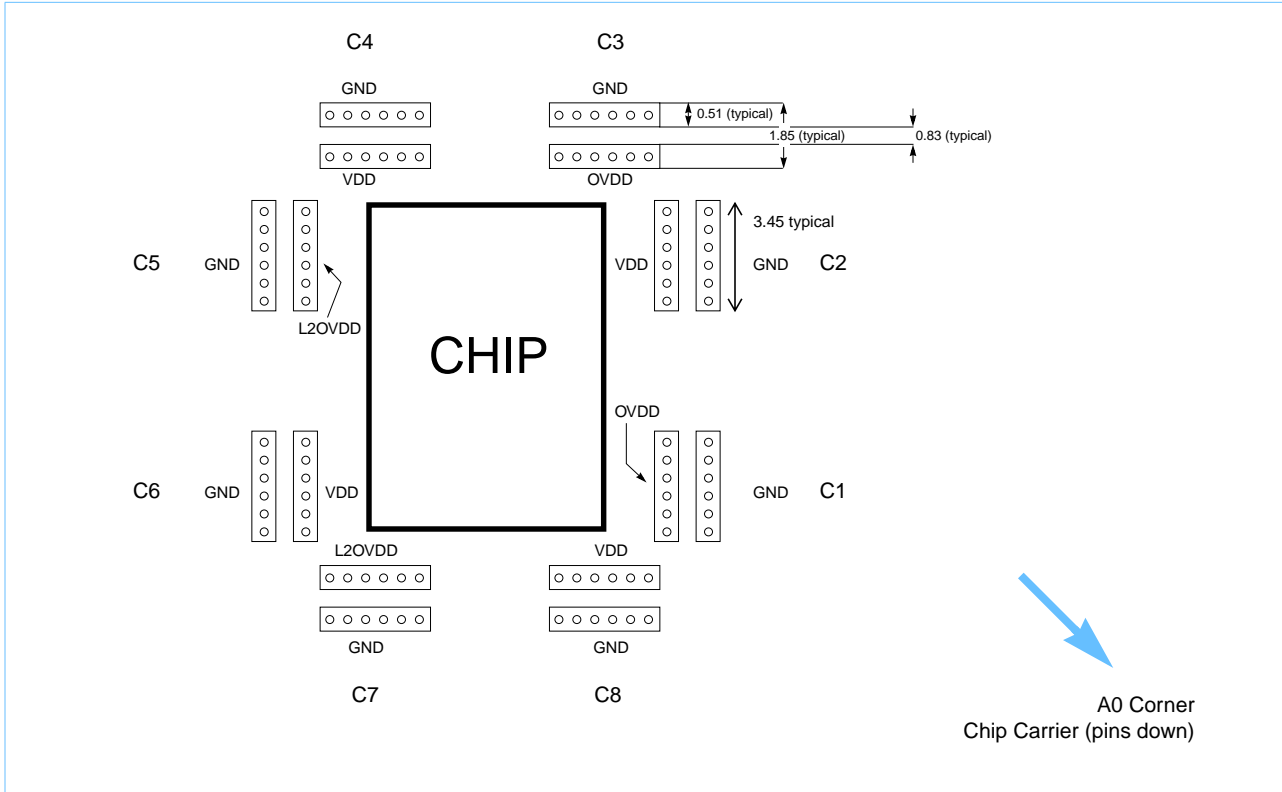


Figure 17. 360 CBGA Decoupling Capacitors





System Design Information

This section provides electrical and thermal design recommendations for successful application of the 750.

PLL Configuration

The 750 PLL is configured by the PLL_CFG[0-3-] signals. For a given SYSCLK (bus) frequency, the PLL configuration signals set the internal CPU and VCO frequency of operation.

750 Microprocessor PLL Configuration

PLL_CFG (0:3)		Processor to Bus Frequency Ratio	VCO Divider ⁵
bin	dec		
0000	0	Rsv ¹	n/a
0001	1	7.5x	2
0010	2	7x	2
0011	3	PLL Bypass ³	n/a
0100	4	2x ⁷	2
0101	5	6.5x	2
0110	6	2.5x ^{6,7}	2
0111	7	4.5x	2
1000	8	3x	2
1001	9	5.5x	2
1010	10	4x	2
1011	11	5x	2
1100	12	8x	2
1101	13	6x	2
1110	14	3.5x	2
1111	15	Off ⁴	n/a

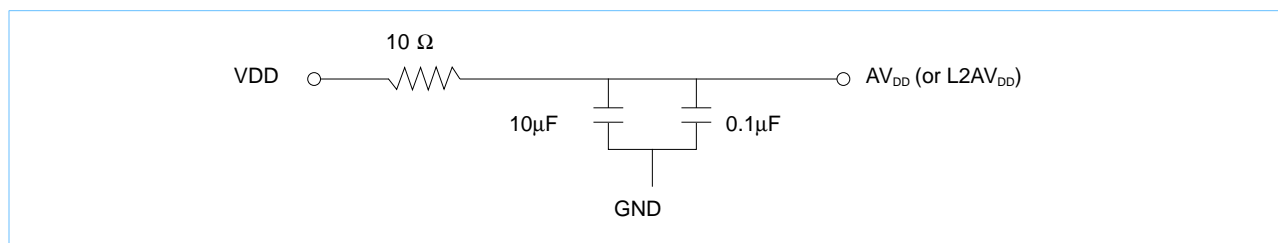
Note:

1. Reserved settings.
2. SYSCLK min is limited by the lowest frequency that manufacturing will support, see Section , "Clock AC Specifications," for valid SYSCLK and VCO frequencies.
3. In PLL-bypass mode, the SYSCLK input signal clocks the internal processor directly, the PLL is disabled, and the bus mode is set for 1:1 mode operation. This mode is intended for factory use only. **Note:** The AC timing specifications given in the document do not apply in PLL-bypass mode.
4. In Clock - off mode, no clocking occurs inside the 750 regardless of the SYSCLK input.
5. The VCO to core clock ratio is 2x for 740/750. This simplifies clock frequency calculations so the user can disregard the VCO frequency. The VCO will operate correctly when the core clock is within specification.
6. 0110 will change from 2.5x in dd2.x to 10x in dd3.x.
7. These values are for dd2.x only. In dd3.x, these PLL.CFG settings may change.

PLL Power Supply Filtering

The AV_{DD} and $L2AV_{DD}$ power signals are provided on the 750 to provide power to the clock generation phase-locked loop and L2 cache delay-locked loop respectively. To ensure stability of the internal clock, the power supplied to the AV_{DD} input signal should be filtered using a circuit similar to the one shown in Figure 18. The circuit should be placed as close as possible to the AV_{DD} pin to ensure it filters out as much noise as possible. An identical but separate circuit should be placed as close as possible to the $L2AV_{DD}$ pin.

Figure 18. PLL Power Supply Filter Circuit



Decoupling Recommendations

Due to the dynamic power management of the 750, which features large address and data buses, as well as high operating frequencies, the 750 can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the 750750 system, and the 750 itself requires a clean, tightly regulated source of power. Therefore, it is strongly recommended that the system designer place at least one decoupling capacitor with a low ESR (effective series resistance) rating at each V_{DD} and OV_{DD} pin (and $L2OV_{DD}$ for the 360 CBGA) of the 750. It is also recommended that these decoupling capacitors receive their power from separate V_{DD} , OV_{DD} and GND power planes in the PCB, utilizing short traces to minimize inductance.

These capacitors should range in value from 220pF to 10 μ F to provide both high and low- frequency filtering, and should be placed as close as possible to their associated V_{DD} or OV_{DD} pins. Suggested values for the V_{DD} pins – 220pF (ceramic), 0.01 μ F (ceramic), and 0.1 μ F (ceramic). Suggested values for the OV_{DD} pins – 0.01 μ F (ceramic), 0.1 μ F (ceramic), and 10 μ F (tantalum). Only SMT (surface-mount technology) capacitors should be used to minimize lead inductance.

In addition, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the V_{DD} and OV_{DD} planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should have a low ESR (equivalent series resistance) rating to ensure the quick response time necessary. They should also be connected to the power and ground planes through two vias to minimize inductance. Suggested bulk capacitors – 100 μ F (AVX TPS tantalum) or 330 μ F (AVX TPS tantalum).

Connection Recommendations

To ensure reliable operation, it is highly recommended to connect unused inputs to an appropriate signal level. Unused active low inputs should be tied to V_{DD} . Unused active high inputs should be connected to GND. All NC (no-connect) signals must remain unconnected.

Power and ground connections must be made to all external V_{DD} , OV_{DD} , and GND, pins of the 750.

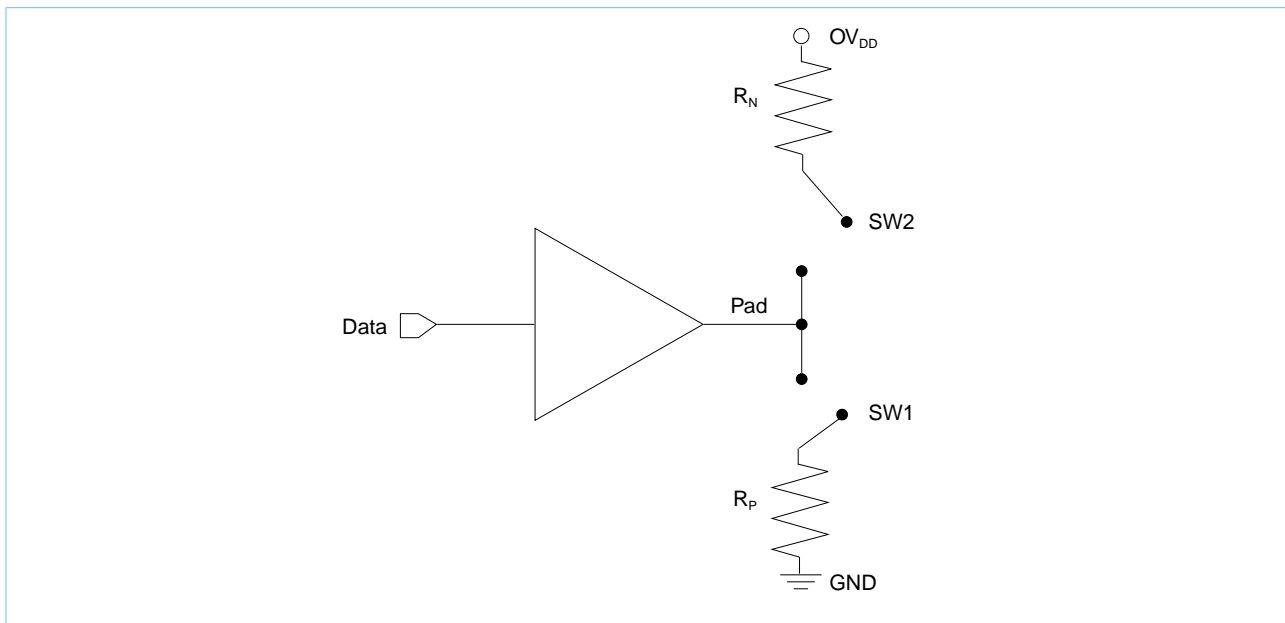
External clock routing should ensure that the rising-edge of the L2 clock is coincident at the CLK input of all SRAMs and at the L2SYNC_IN input of the 750. The L2CLKOUTA network could be used only, or the L2CLKOUTB network could also be used depending on the loading, frequency, and number of SRAMs.

Output Buffer DC Impedance

The 750 60x and L2 I/O drivers were characterized over process, voltage, and temperature. To measure Z_0 , an external resistor is connected to the chip pad, either to OV_{DD} or GND. Then the value of such resistor is varied until the pad voltage is $OV_{DD}/2$; see Figure 19, "Driver Impedance Measurement," below.

The output impedance is actually the average of two components, the resistances of the pull-up and pull-down devices. When Data is held low, SW1 is closed (SW2 is open), and R_N is trimmed until Pad = $OV_{DD}/2$. R_N then becomes the resistance of the pull-down devices. When Data is held high, SW2 is closed (SW1 is open), and R_P is trimmed until Pad = $OV_{DD}/2$. R_P then becomes the resistance of the pull-up devices. With a properly designed driver R_P and R_N are close to each other in value, then $Z_0 = (R_P + R_N)/2$.

Figure 19. Driver Impedance Measurement



The following table summarizes the impedance a board designer would design to for a typical process. These values were derived by simulation at 65°C. As the process improves, the output impedance will be lower by several ohms than this typical value.

Impedance Characteristics

$V_{DD} = 1.9V_{DC}$, $L2OV_{DD}=OV_{DD} = 3.3V_{DC}$, $T_j = 65^\circ C$

Process	60x	L2	Symbol	Unit
Typical	43	38	Z_0	Ω

Pull-up Resistor Requirements

The 750 requires high-resistive (weak: 10K Ω) pull-up resistors on several control signals of the bus interface to maintain the control signals in the negated state after they have been actively negated and released by the 750 or other bus masters. These signals are: \overline{TS} , \overline{ABB} , \overline{DBB} , $\overline{TT[0:4]}$, \overline{TBST} , \overline{GBL} , and \overline{ARTRY} .

In addition, the 750 has one open-drain style output that requires a pull-up resistor (weak or stronger: 4.7K Ω - 1- K Ω) if it is used by the system. This signal is: $\overline{CKSTP_OUT}$.

The data bus input receivers are normally turned off when no read operation is in progress and do not require pull-up resistors on the data bus. Other data bus receivers in the system, however, may require pull-ups, or that those signals be otherwise driven by the system during inactive periods. The data bus signals are: $\overline{DH[0-31]}$, $\overline{DL[0-31]}$, and $\overline{DP[0-7]}$.

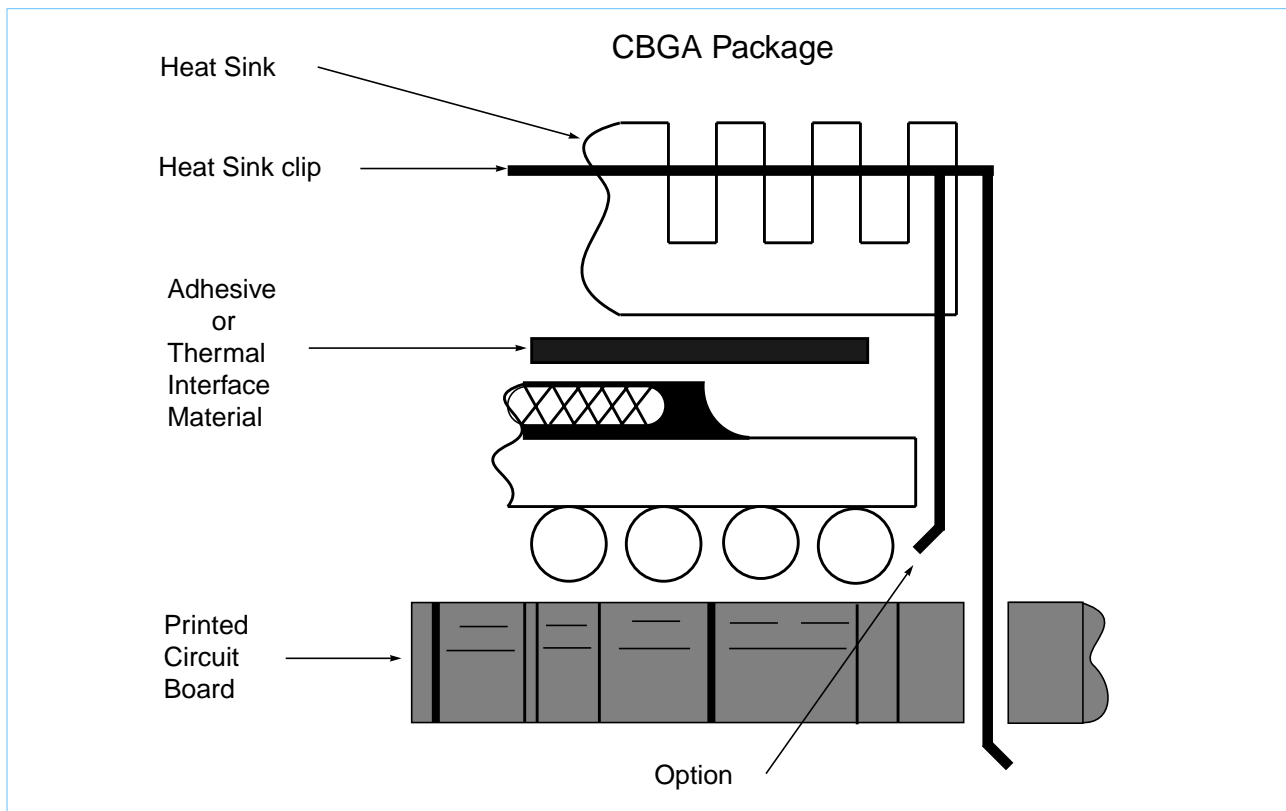
If address or data parity is not used by the system, and the respective parity checking is disabled through $\overline{HID0}$, the input receivers for those pins are disabled, and those pins do not require pull-up resistors and should be left unconnected by the system. If all parity generation is disabled through $\overline{HID0}$, then all parity checking should also be disabled through $\overline{HID0}$, and all parity pins may be left unconnected by the system.

No pull-up resistors are normally required for the L2 interface.

Thermal Management Information

This section provides thermal management information for the CBGA package for air cooled applications. Proper thermal control design is primarily dependent upon the system-level design; that is, the heat sink, air flow, and the thermal interface material. To reduce the die-junction temperature, heat sinks may be attached to the package by several methods: adhesive, spring clip to holes in the printed-circuit board or package, and mounting clip and screw assembly, see Figure 20.

Figure 20. Package Exploded Cross-Sectional View with Several Heat Sink Options



Maximum Heatsink Weight Limit for the 360 CBGA

Force	Maximum (pounds)
Dynamic Compression	10.0
Dynamic Tensile	2.5
Static Constant (Spring Force)	8.2

The board designer can choose between several types of heat sinks to place on the 750. There are several commercially-available heat sinks for the 750 provided by the following vendors:

Chip Coolers, Inc. 333 Strawberry Field Rd. Warwick, RI 02887-6979	800-227-0254 (USA/Canada) 401-739-7600
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Thermalloy 2021 W. Valley View Lane P.O. Box 810839 Dallas, TX 75731	214-243-4321
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International Electronic Research Corporation (IERC) 135 W. Magnolia Blvd. Burbank, CA 91502	818-842-7277
--	--------------

Aavid Engineering One Kool Path Laconic, NH 03247-0440	603-528-3400
--	--------------

Wakefield Engineering 60 Audubon Rd. Wakefield, MA 01880	617-245-5900
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Ultimately, the final selection of an appropriate heat sink for the 750 depends on many factors, such as thermal performance at a given air velocity, spatial volume, mass, attachment method, assembly, and cost.

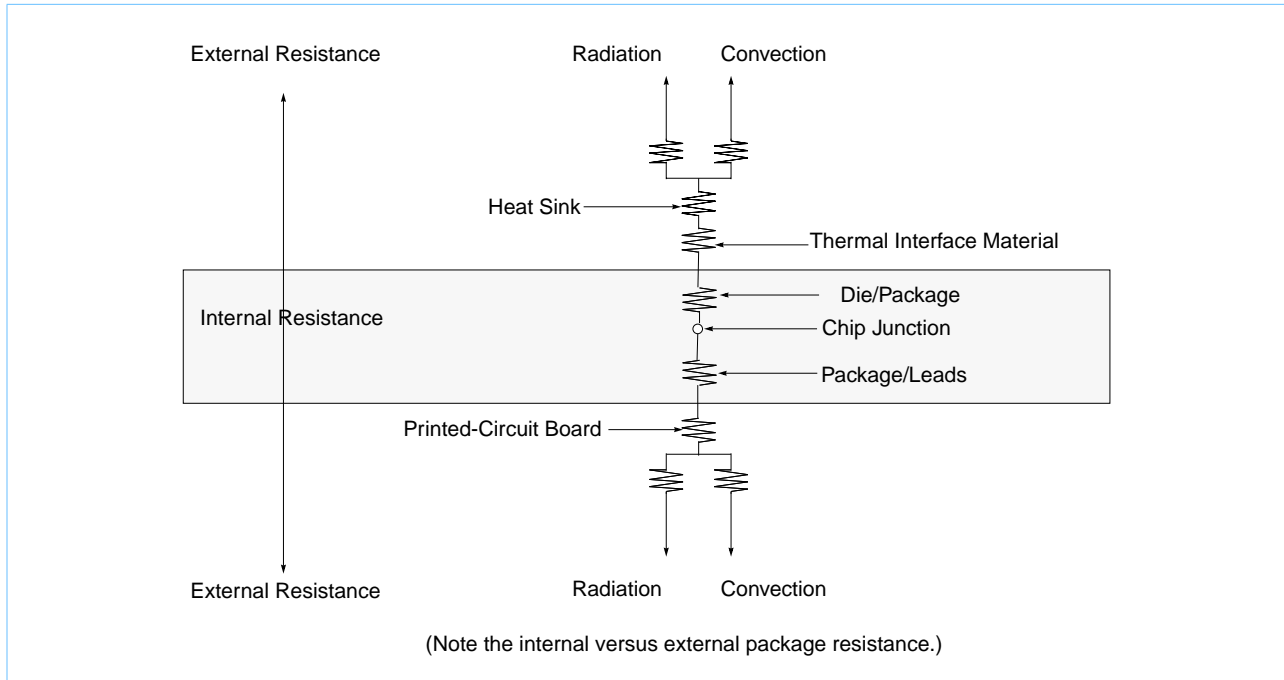
Internal Package Conduction Resistance

For the exposed-die packaging technology, shown in Table "Package Thermal Characteristics1," on page 8, the intrinsic conduction thermal resistance paths are as follows.

- Die junction-to-case thermal resistance
- Die junction-to-ball thermal resistance

Figure 21 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.

Figure 21. C4 Package with Heat Sink Mounted to a Printed-Circuit Board



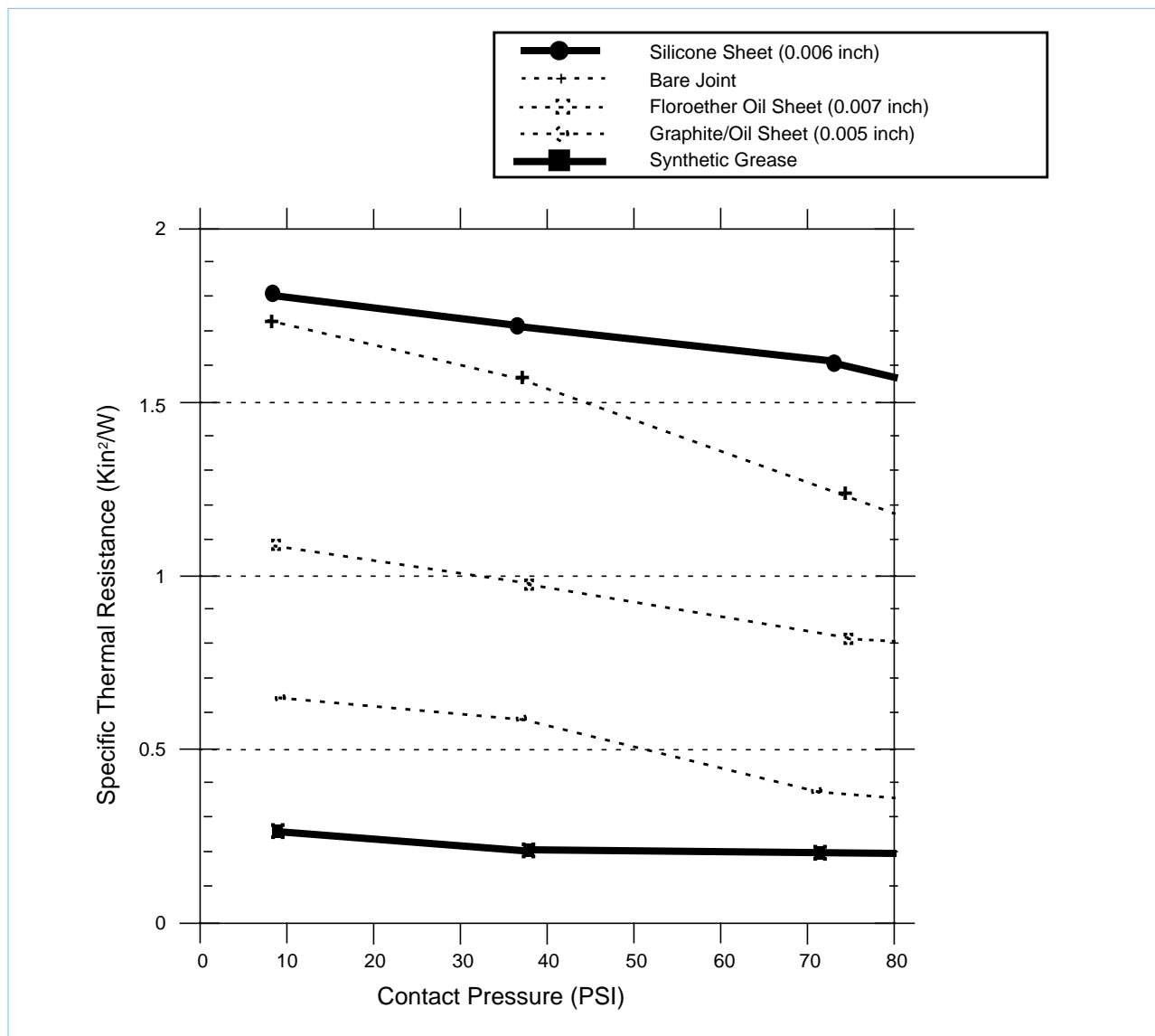
Heat generated on the active side (ball) of the chip is conducted through the silicon, then through the heat sink attach material (or thermal interface material), and finally to the heat sink; where it is removed by forced-air convection. Since the silicon thermal resistance is quite small, for a first-order analysis, the temperature drop in the silicon may be neglected. Thus, the heat sink attach material and the heat sink conduction/conductive thermal resistances are the dominant terms.

Adhesives and Thermal Interface Materials

A thermal interface material is recommended at the package lid-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by a spring clip mechanism, Figure 22 shows the thermal performance of three thin-sheet thermal-interface materials (silicon, graphite/oil, fluoroether oil), a bare joint, and a joint with thermal grease, as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. That is, the bare joint results in a thermal resistance approximately 7 times greater than the thermal grease joint.

Heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 20). Therefore the synthetic grease offers the best thermal performance, considering the low interface pressure. Of course, the selection of any thermal interface material depends on many factors – thermal performance requirements, manufacturability, service temperature, dielectric properties, cost, etc.

Figure 22. Thermal Performance of Select Thermal Interface Material



The board designer can choose between several types of thermal interfaces. Heat sink adhesive materials should be selected based upon high conductivity, yet adequate mechanical strength to meet equipment shock/vibration requirements. There are several commercially-available thermal interfaces and adhesive materials provided by the following vendors.

Dow-Corning Corporation
 Dow-Corning Electronic Materials
 P.O. Box 0997
 Midland, MI 48686-0997

517-496-4000



Chomerics, Inc. 77 Dragon Court Woburn, MA 01888-4850	617-935-4850
Thermagon, Inc. 3256 West 25th Street Cleveland, OH 44109-1668	216-741-7659
Loctite Corporation 1001 Trout Brook Crossing Rocky Hill, CT 06067	860-571-5100
AI Technology (e.g. EG7655) 1425 Lower Ferry Road Trent, NJ 08618	609-882-2332

The following section provides a heat sink selection example using one of the commercially available heat sinks.

Heat Sink Selection Example

For preliminary heat sink sizing, the die-junction temperature can be expressed as follows.

$$T_J = T_A + T_R + (\theta_{JC} + \theta_{INT} + \theta_{SA}) \times P_D$$

Where:

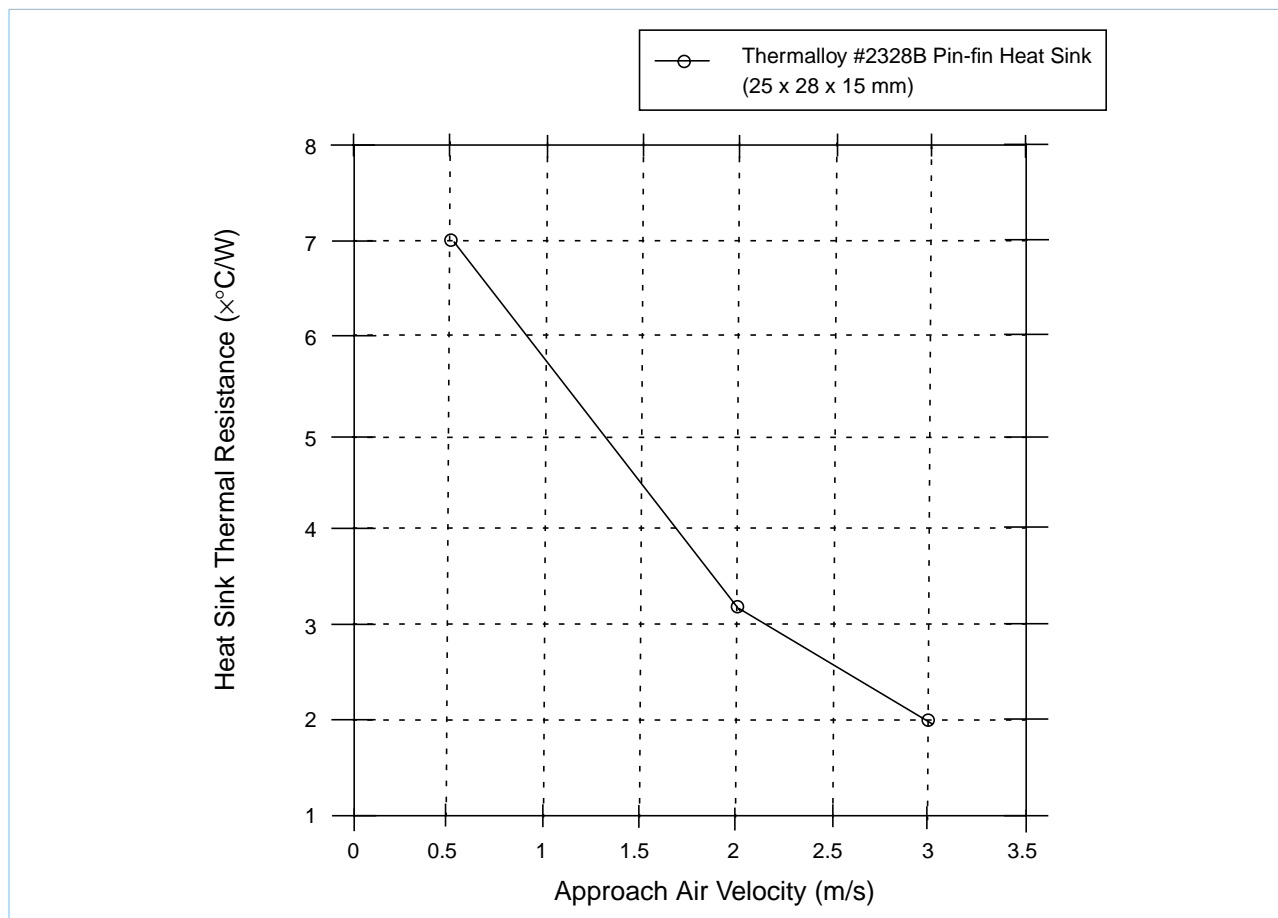
- T_J is the die-junction temperature
- T_A is the inlet cabinet ambient temperature
- T_R is the air temperature rise within the system cabinet
- θ_{JC} is the junction-to-case thermal resistance
- θ_{INT} is the thermal resistance of the thermal interface material
- θ_{SA} is the heat sink-to-ambient thermal resistance
- P_D is the power dissipated by the device

Typical die-junction temperatures (T_J) should be maintained less than the value specified in Table "Package Thermal Characteristics1," on page 8. The temperature of the air cooling the component greatly depends upon the ambient inlet air temperature and the air temperature rise within the computer cabinet. An electronic cabinet inlet-air temperature (T_A) may range from 30 to 40°C. The air temperature rise within a cabinet (T_R) may be in the range of 5 to 10°C. The thermal resistance of the interface material (θ_{INT}) is typically about 1°C/W. Assuming a T_A of 30°C, a T_R of 5°C, a CBGA package $\theta_{JC} = 0.03$, and a power dissipation (P_D) of 5.0 watts, the following expression for T_J is obtained.

$$\text{Die-junction temperature: } T_J = 30^\circ\text{C} + 5^\circ\text{C} + (0.03^\circ\text{C/W} + 1.0^\circ\text{C/W} + \theta_{SA}) \times 5\text{W}$$

For a Thermalloy heat sink #2328B, the heat sink-to-ambient thermal resistance (θ_{SA}) versus air flow velocity is shown in Figure 23.

Figure 23. Thermalloy #2328B Pin-Fin Heat Sink-to-Ambient Thermal Resistance vs. Air flow Velocity



Assuming an air velocity of 0.5m/s, we have an effective θ_{SA} of 7°C/W, thus

$$T_J = 30^\circ\text{C} + 5^\circ\text{C} + (.03^\circ\text{C/W} + 1.0^\circ\text{C/W} + 7^\circ\text{C/W}) \times 4.5\text{W},$$

resulting in a junction temperature of approximately 71°C which is well within the maximum operating temperature of the component.

Other heat sinks offered by Chip Coolers, IERC, Thermalloy, Aavid, and Wakefield Engineering offer different heat sink-to-ambient thermal resistances, and may or may not need air flow.

Though the junction-to-ambient and the heat sink-to-ambient thermal resistances are a common figure-of-merit used for comparing the thermal performance of various microelectronic packaging technologies, one should exercise caution when only using this metric in determining thermal management because no single parameter can adequately describe three-dimensional heat flow. The final chip-junction operating temperature is not only a function of the component-level thermal resistance, but the system-level design and its operating conditions. In addition to the component's power dissipation, a number of factors affect the final operating die-junction temperature. These factors might include air flow, board population (local heat flux of adjacent components), heat sink efficiency, heat sink attach, next-level interconnect technology, system air temperature rise, etc.



Ordering Information

This section provides the part numbering nomenclature for the 750. Note that the individual part numbers correspond to a maximum processor core frequency. For available devices contact your local IBM sales office.

Figure 24. IBM Part Number Key for 740

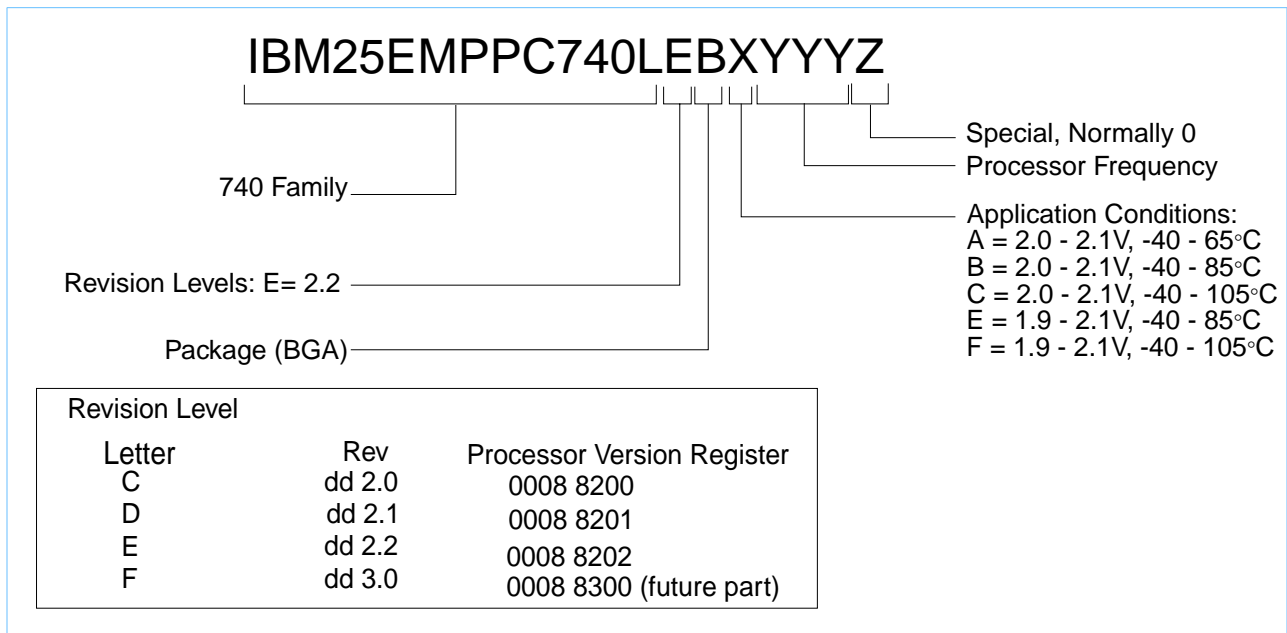
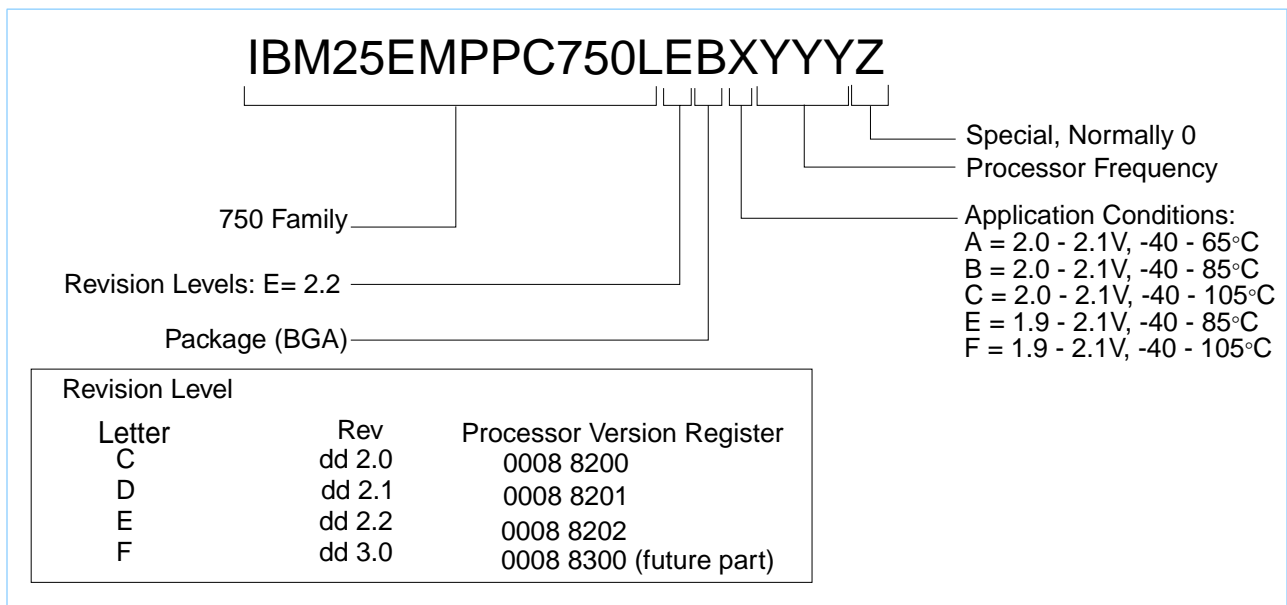


Figure 25. IBM Part Number Key for 750





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